

MPPC & SPAD

Future of Photon Counting Detectors

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Introduction

Terminology

PD – Photodiode

APD – Avalanche photodiode

SPAD – Single-photon avalanche photodiode

SPPC – Single-pixel photon counter; another name for SPAD

} The same

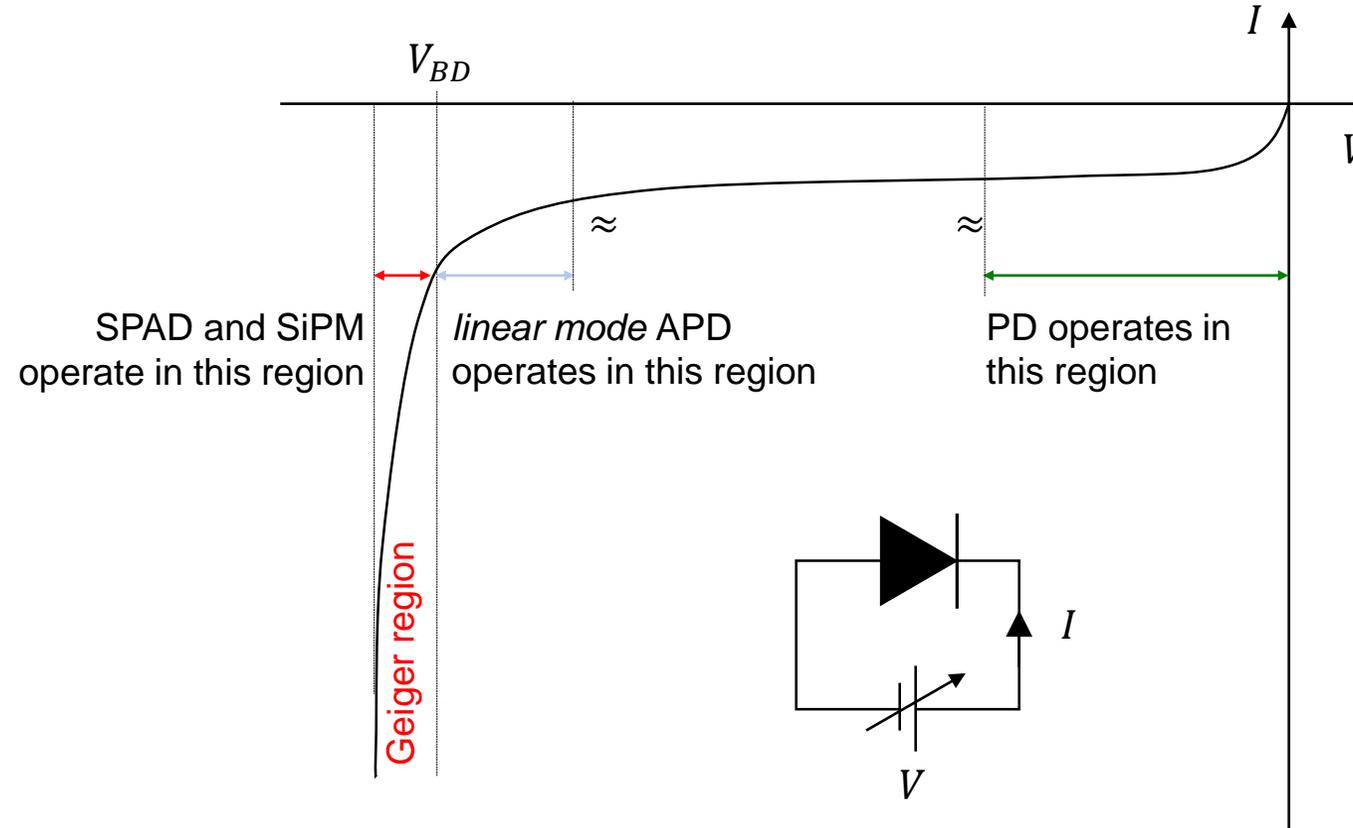
SiPM – Silicon photomultiplier

MPPC – Multi-pixel photon counter; another name for SiPM

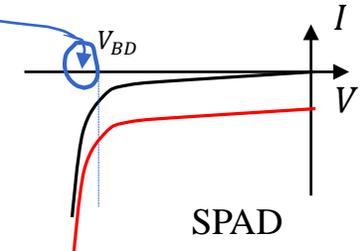
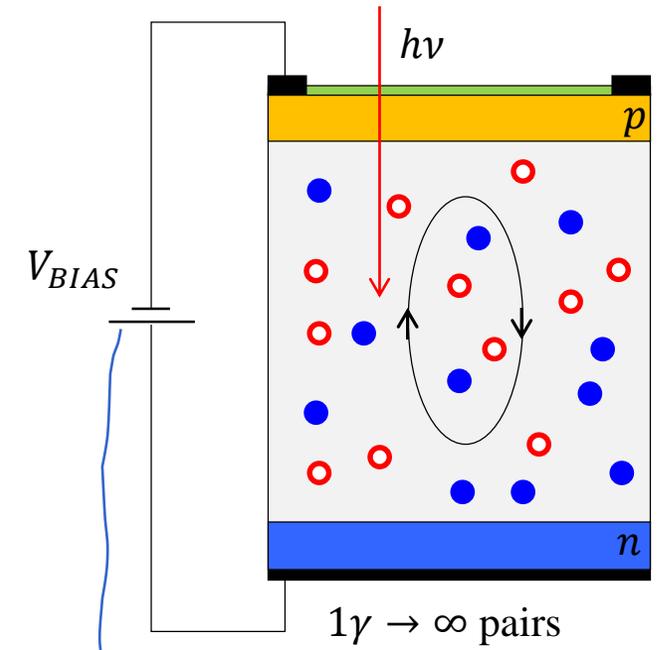
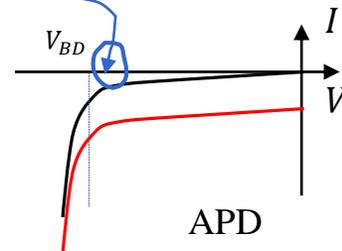
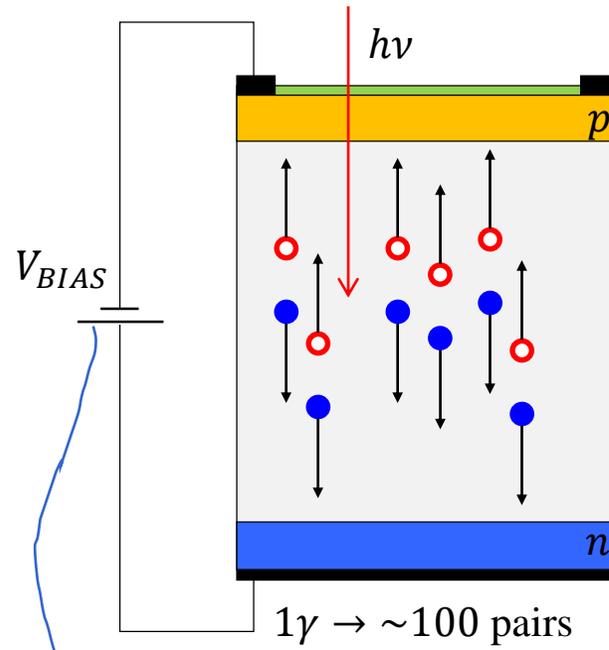
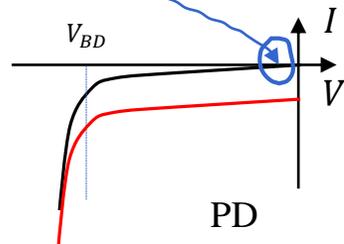
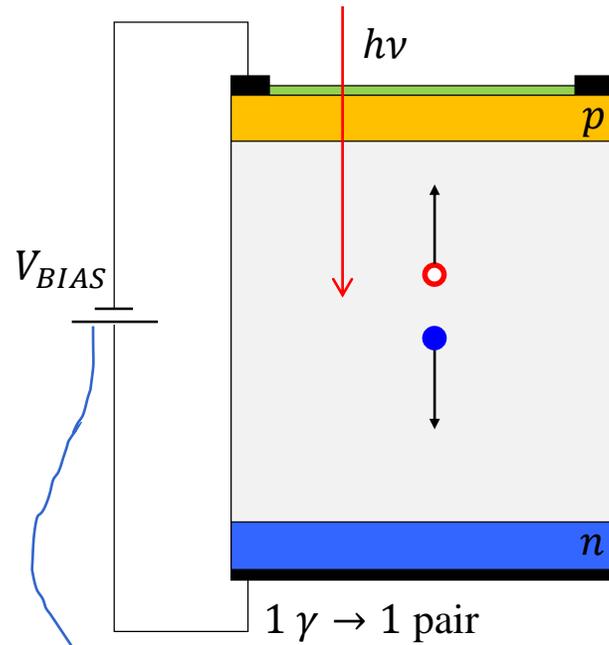
} The same

PMT – Photomultiplier tube

Generic PN junction: modes of operation

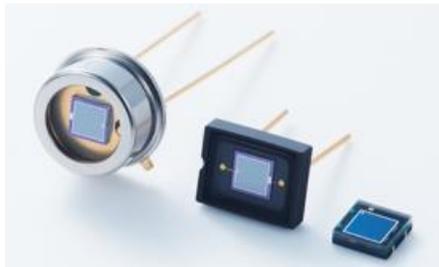


PN junction devices

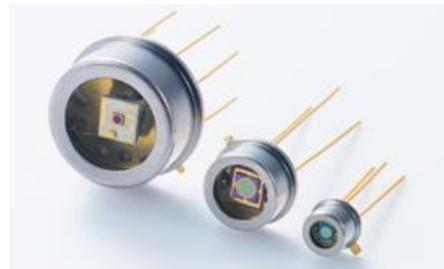


Attributes of a photodiode

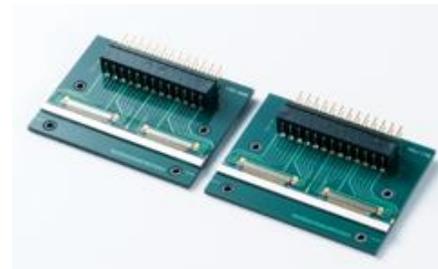
1. Detector of choice for sufficiently high input light level
2. Wide spectral coverage (from UV to IR) for a family of photodiodes
3. Inexpensive and easy to use
4. Low intrinsic noise
5. Can be used in arrays and available in modules



Si PDs



InGaAS PDs



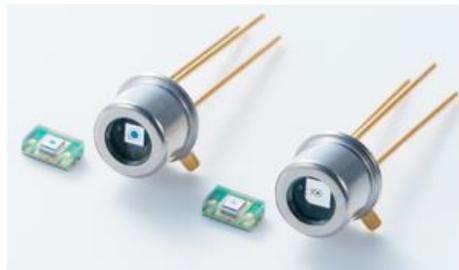
PD arrays with
amplifier



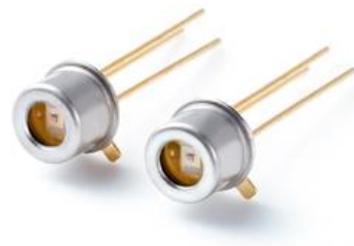
PD module

Attributes of an avalanche photodiode (linear mode)

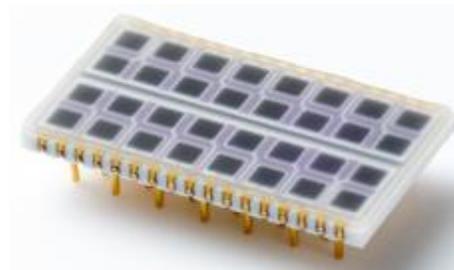
1. Detector of choice for light levels too high for a PMT/SiPM but too low for a photodiode
2. Intrinsic gain up to ~ 100
3. Wide spectral coverage ($200\text{ nm} - 1700\text{ nm}$) for a family of avalanche photodiodes
4. Can be used in arrays
5. Available as part of a module



Si APDs



InGaAs APDs



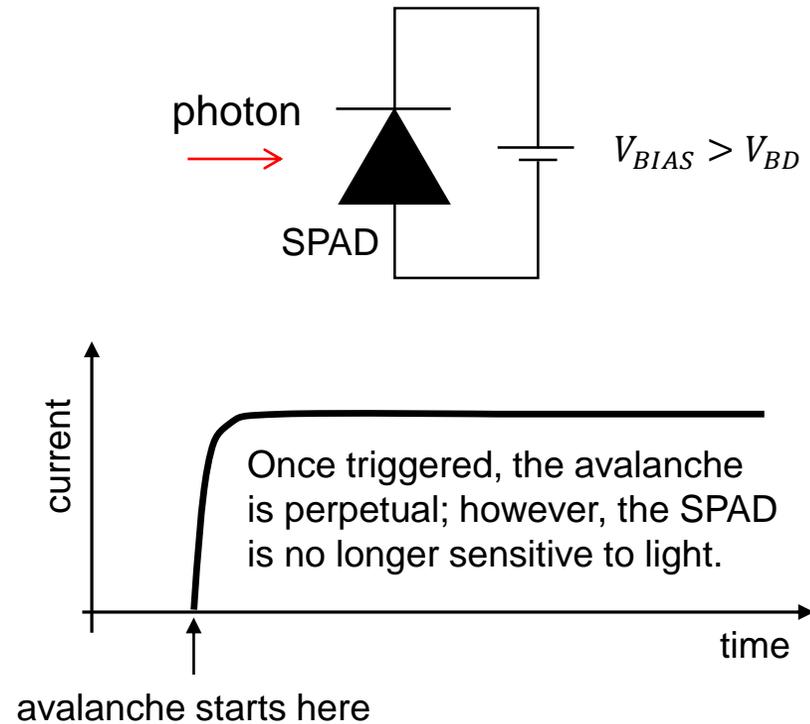
Si APD array



APD module

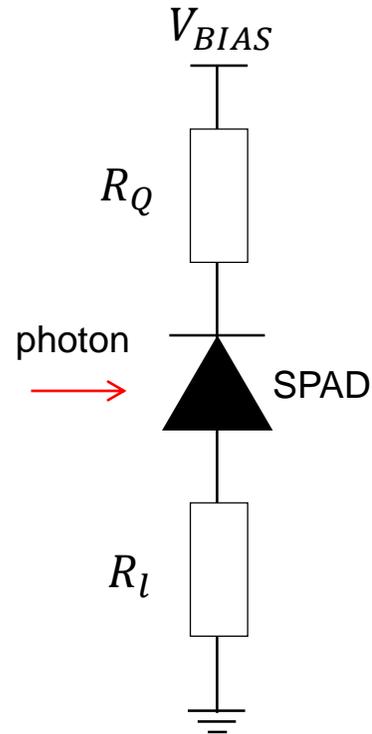
Single-Photon Avalanche Photodiode (SPAD)

Operation of a SPAD

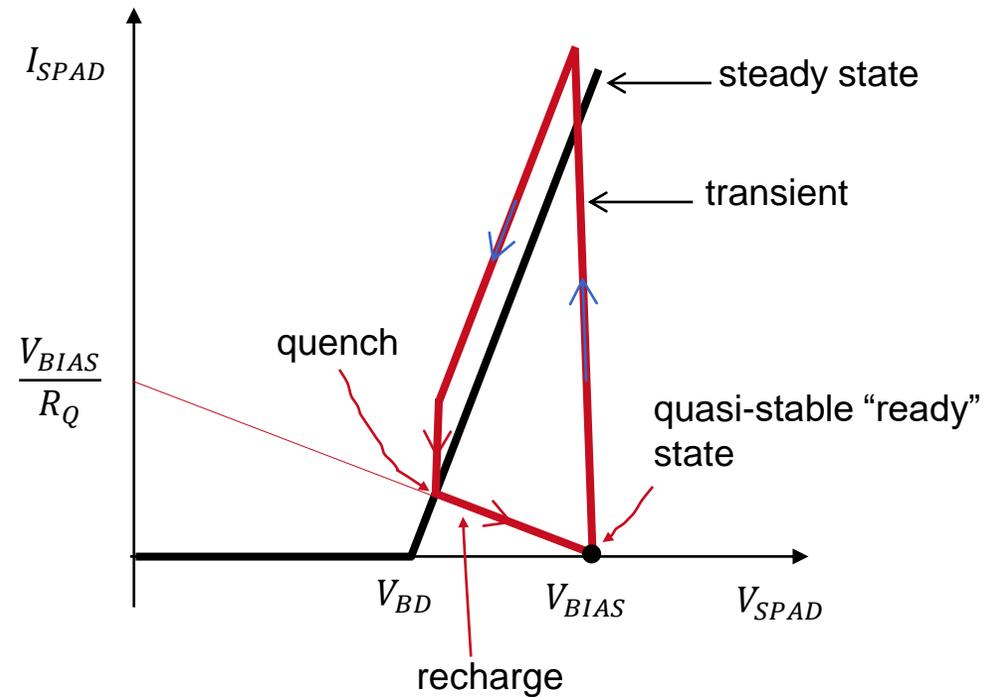


Without quenching, SPAD operates as a light switch.

Operation of a SPAD (passive quenching)



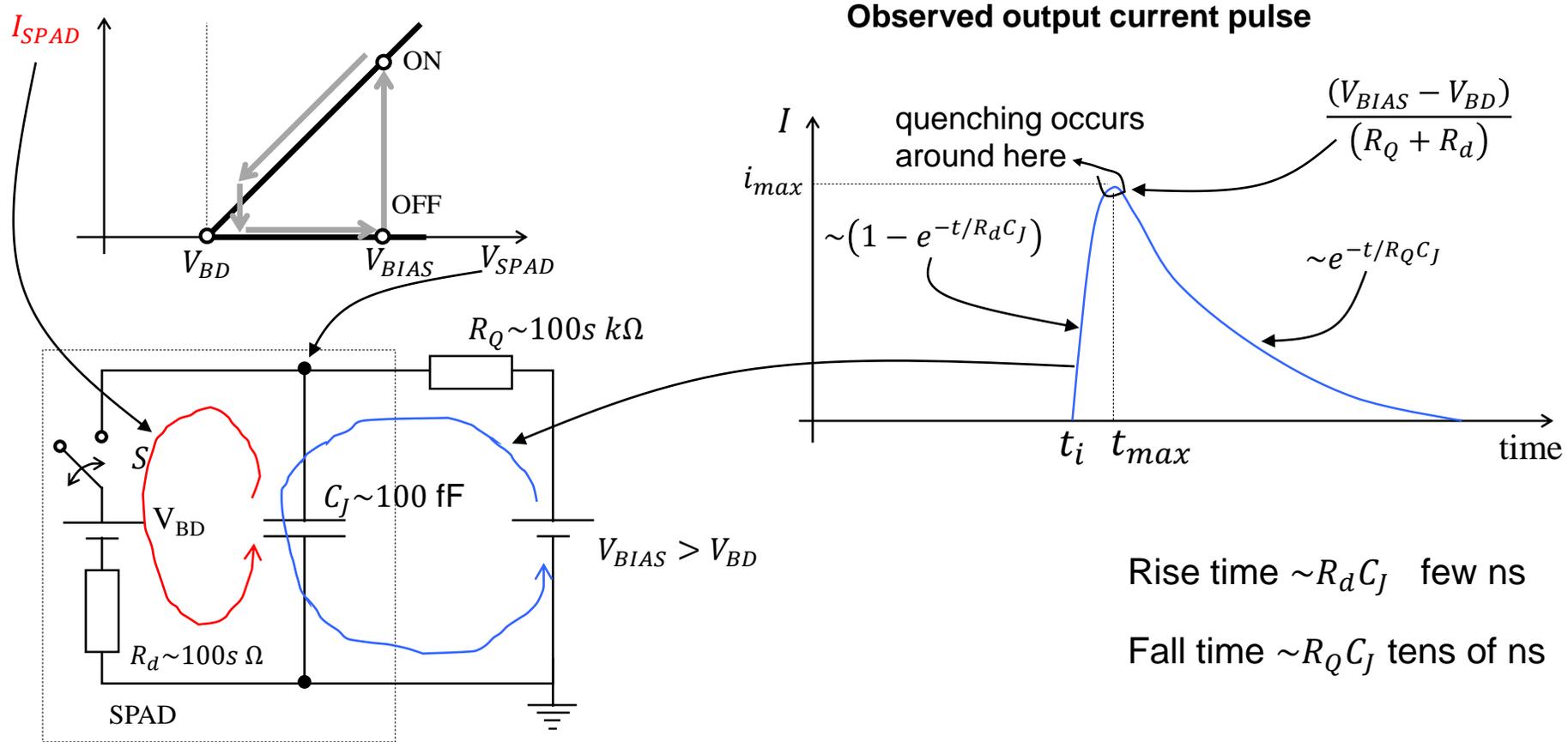
$$R_Q \gg R_L$$



R_Q must be large enough to ensure quenching.

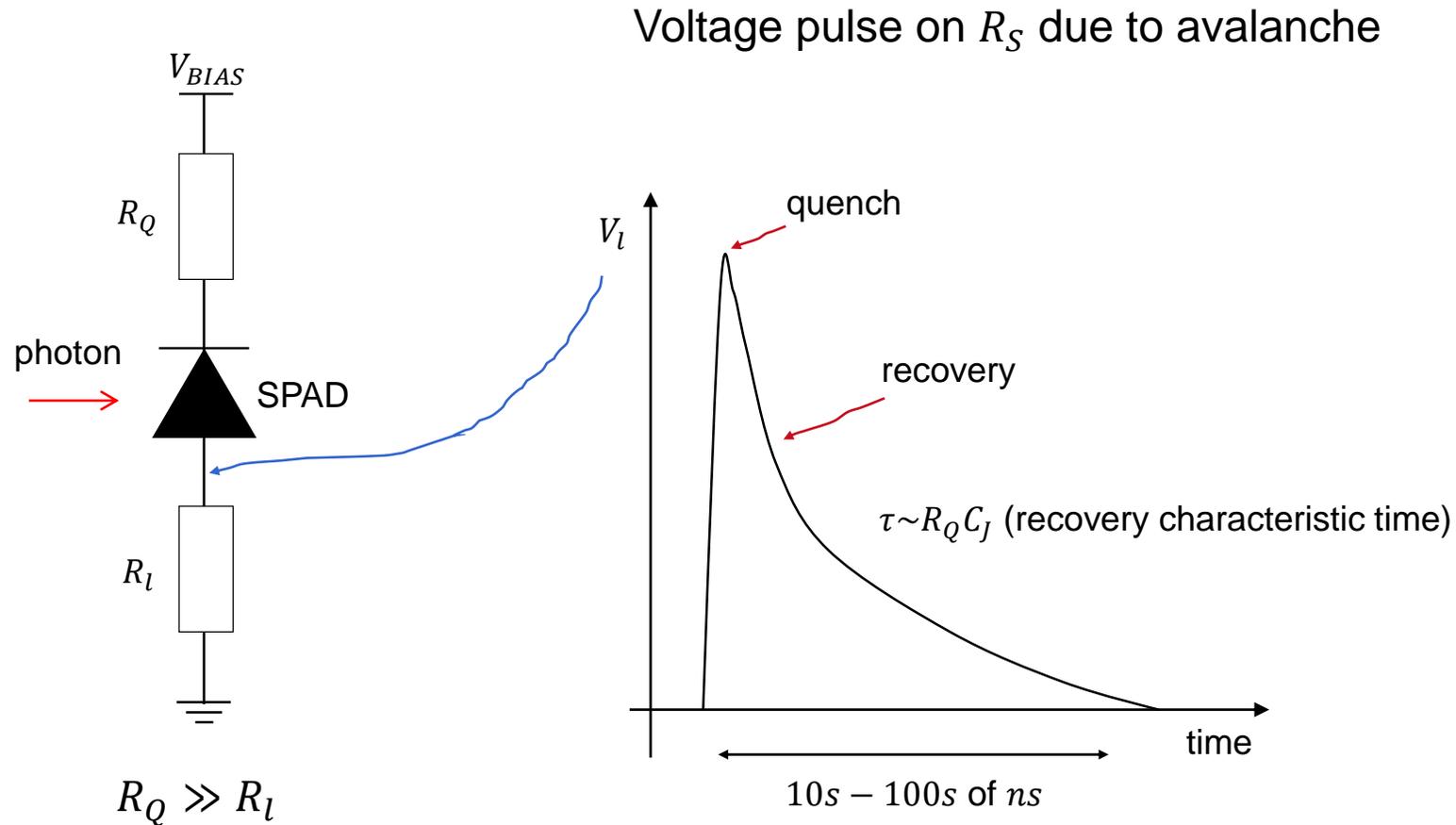
$$\Delta V = V_{BIAS} - V_{BD} \text{ (overvoltage)}$$

Operation of a SPAD (passive quenching)

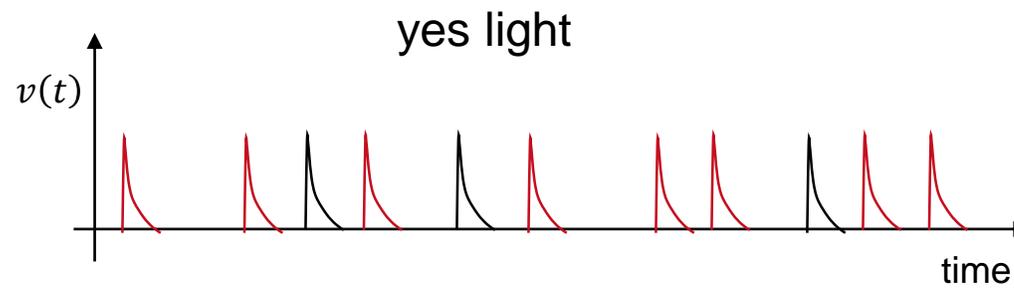
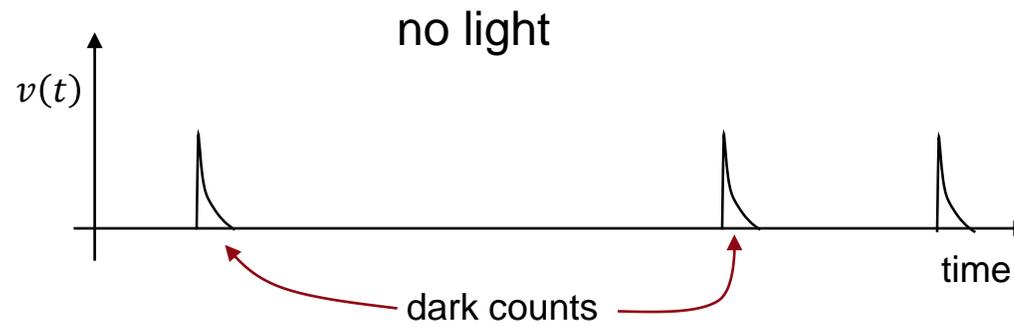
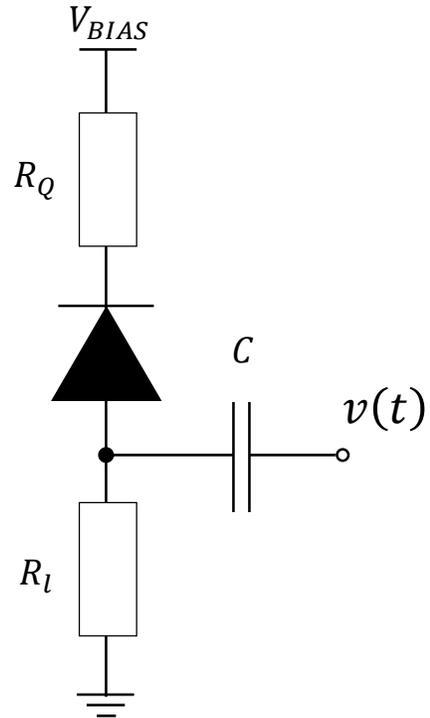


$$\mu = \frac{i_{max} R_Q C_J}{e} = \frac{(V_{BIAS} - V_{BD}) R_Q C_J}{e(R_Q + R_d)} \approx \frac{(V_{BIAS} - V_{BD}) C_J}{e} = \boxed{\frac{\Delta V C_J}{e}} \quad (\text{gain})$$

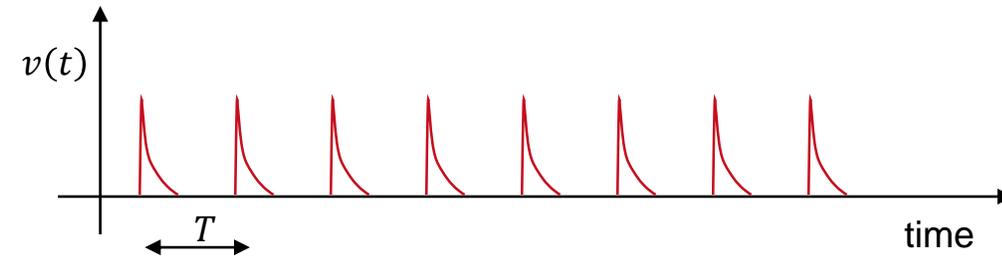
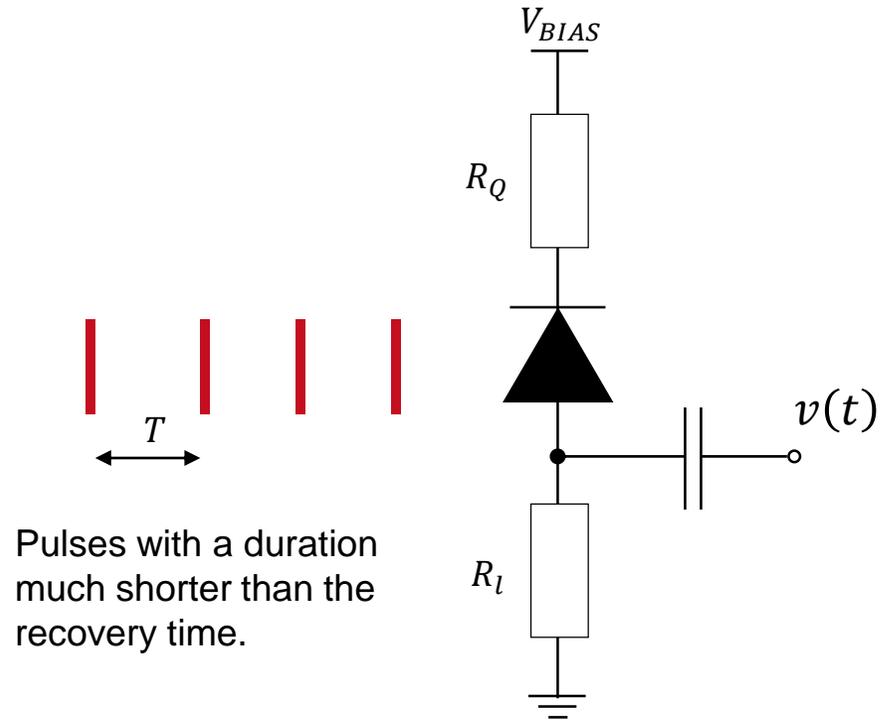
Operation of a SPAD (passive quenching)



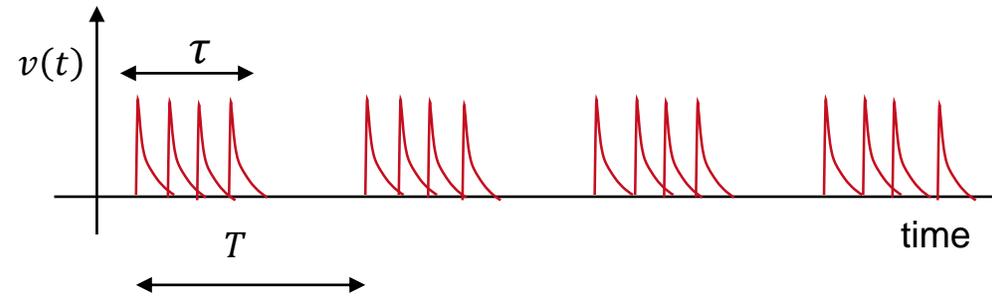
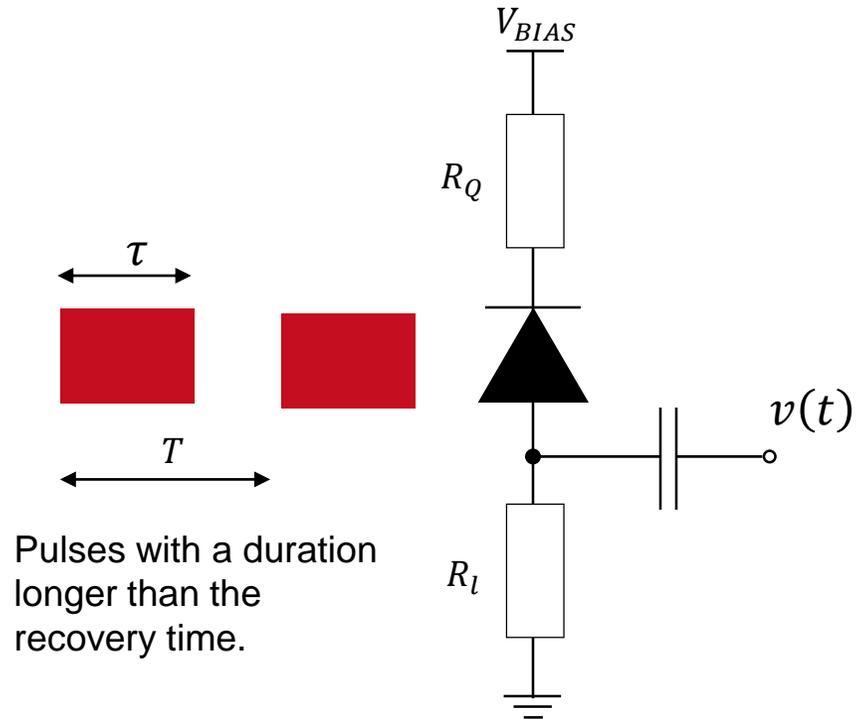
Photon counting with SPAD



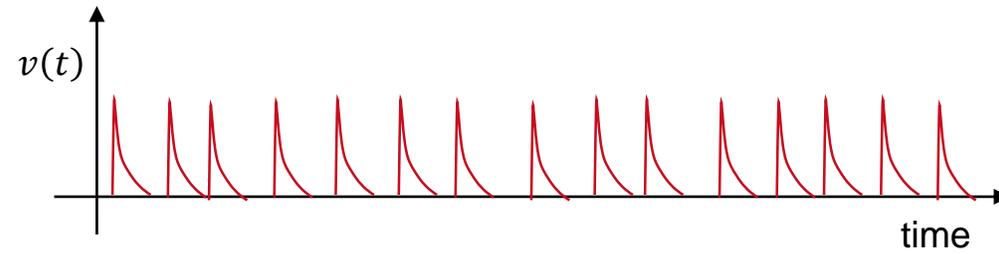
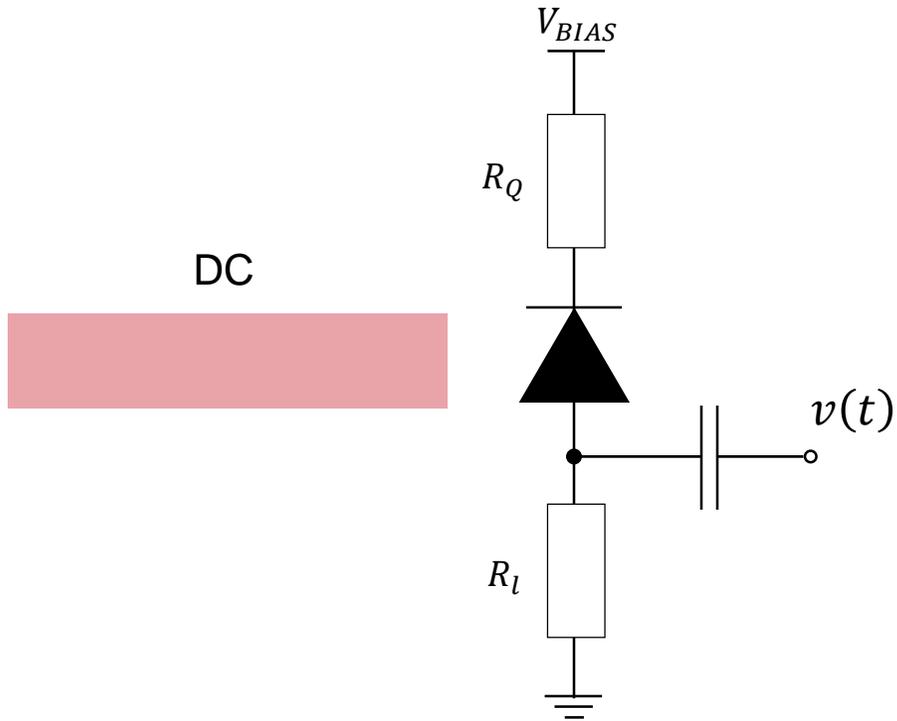
Photon counting with SPAD



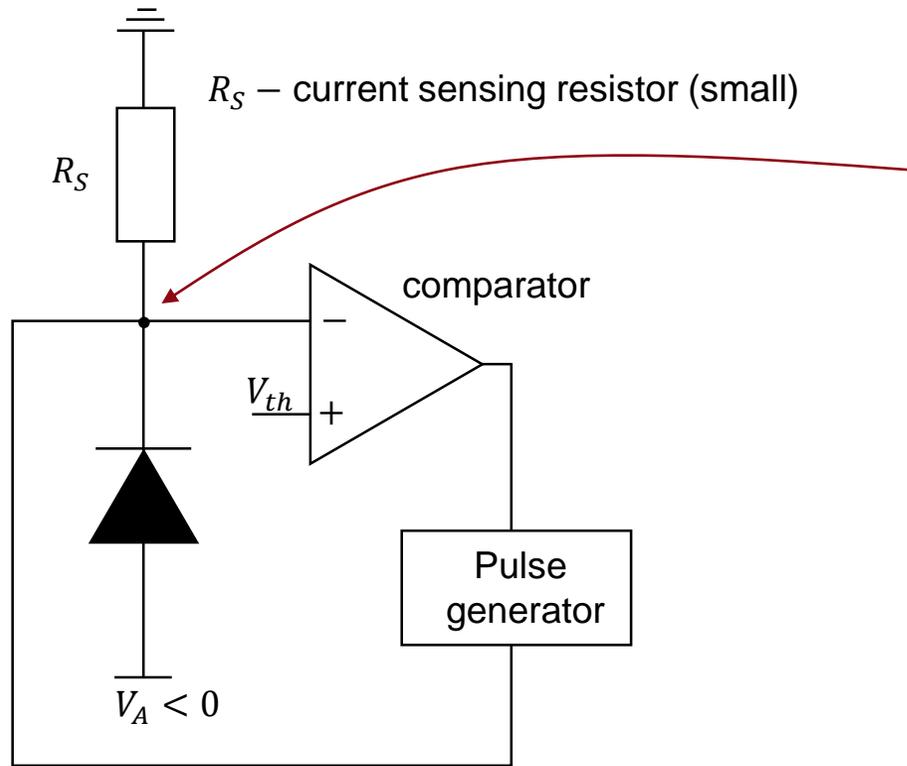
Photon counting with SPAD



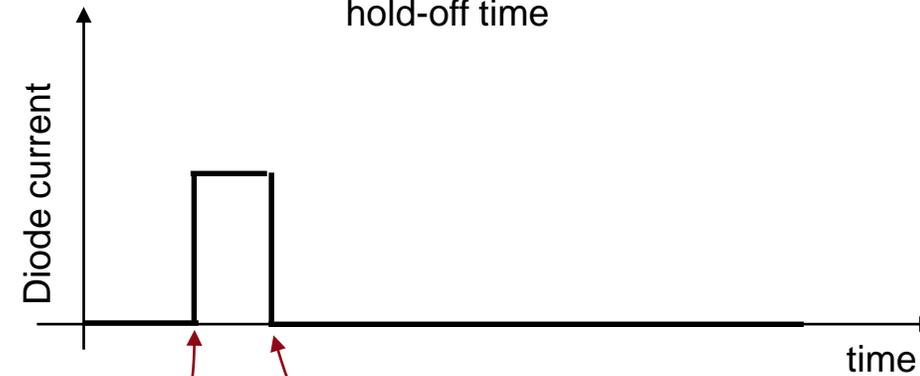
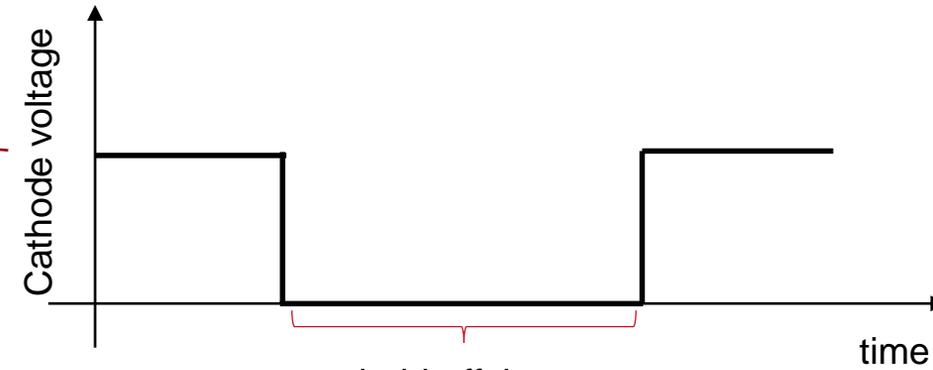
Photon counting with SPAD



Active quenching



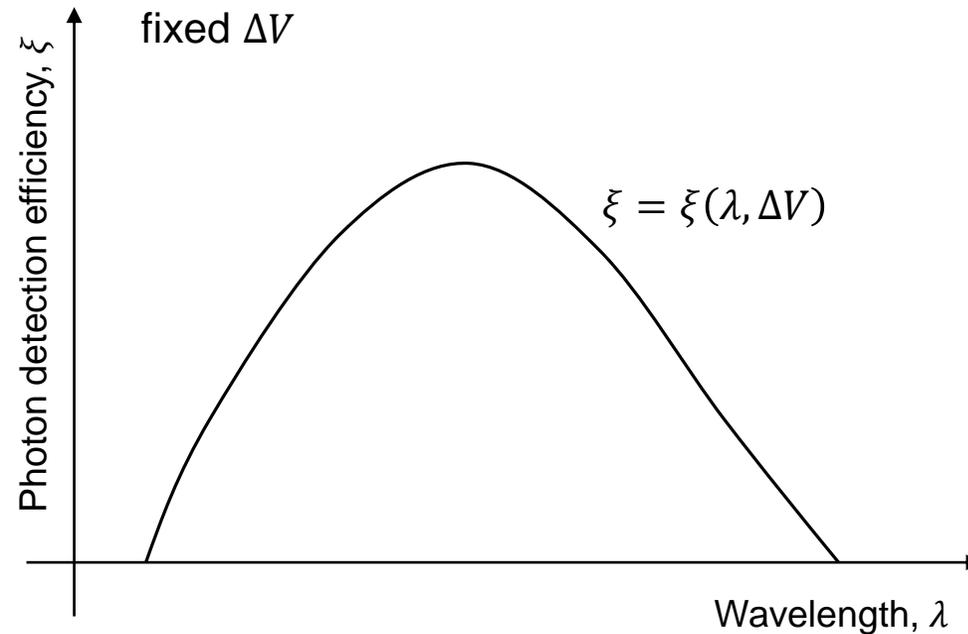
Basic concept of active quenching.



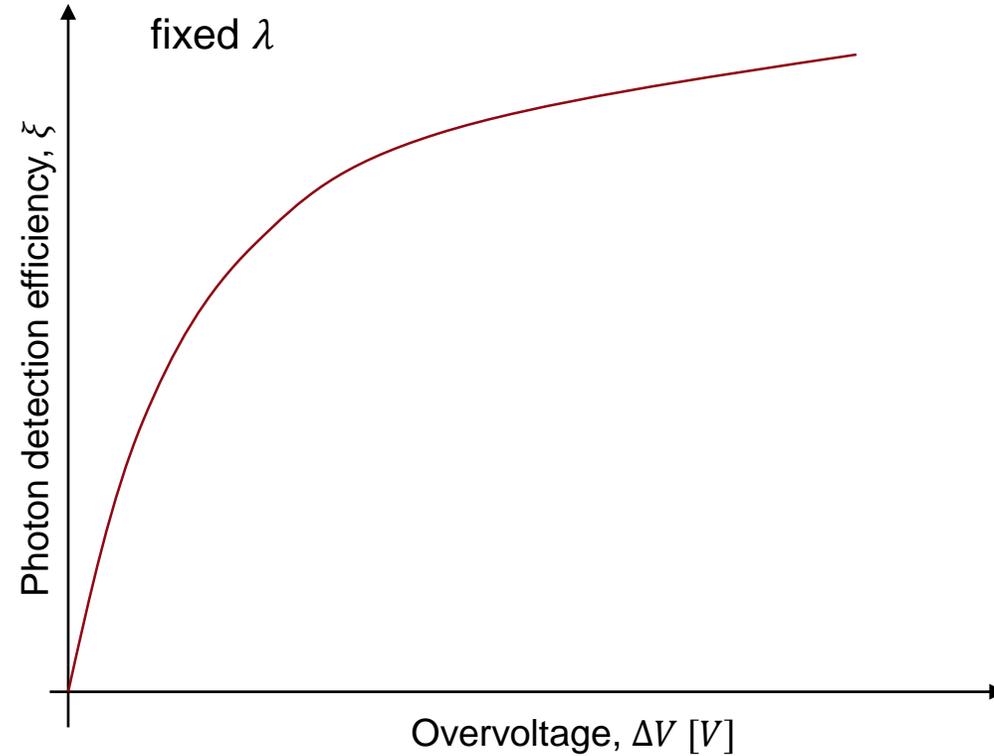
avalanche starts here

quenching occurs here

Reference: "Progress in Quenching Circuits for Single Photon Avalanche Diodes," Gallivanoni, A., Rech, I., & Ghioni, M., IEEE Transactions on Nuclear Science, Vol. 57, No. 6, December 2010

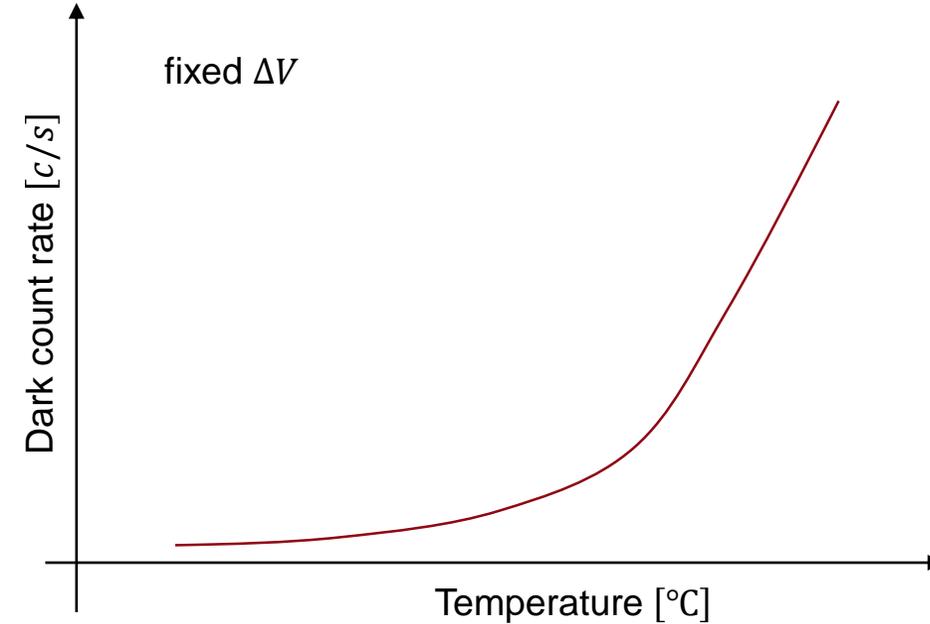
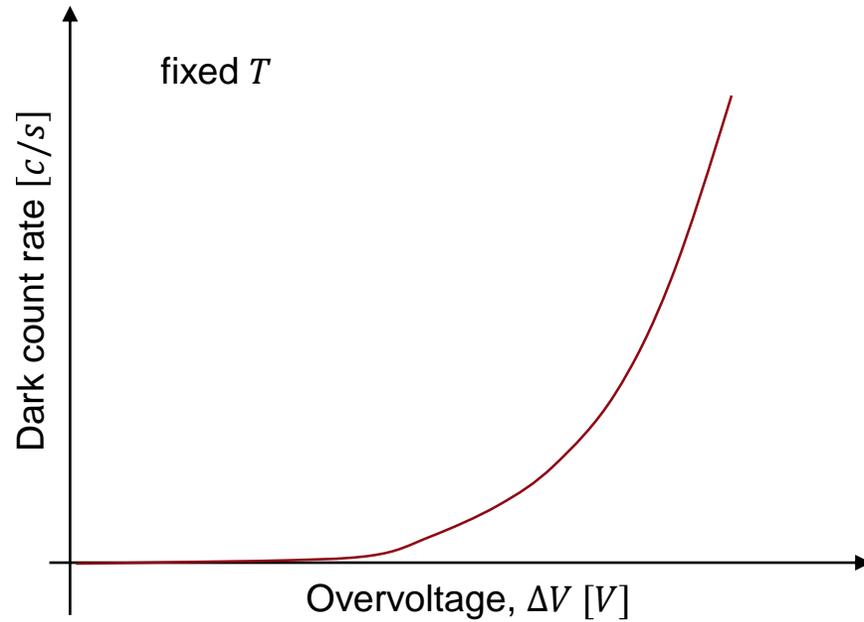


Photon detection efficiency is a probability that the incident photon is detected. It is a function of wavelength and overvoltage.



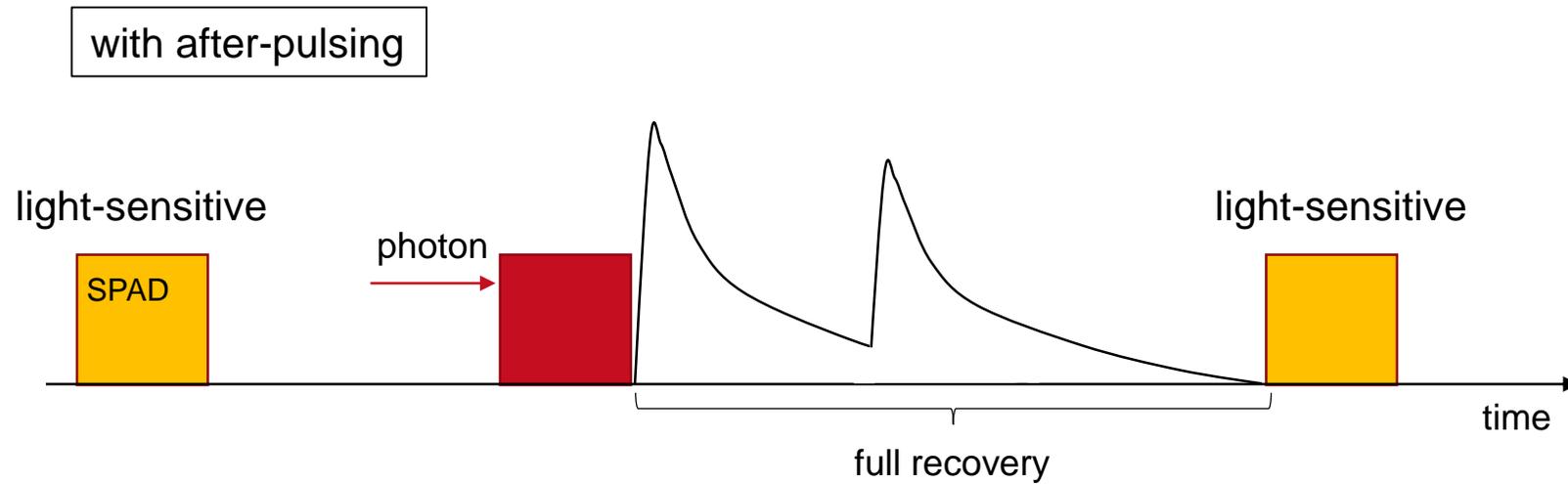
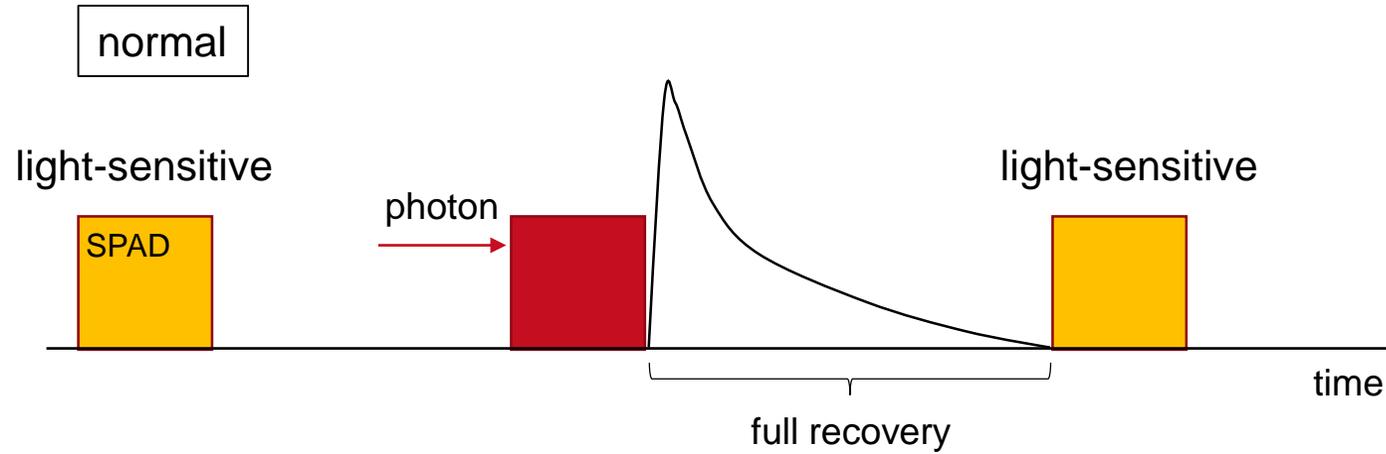
For a given wavelength, photon detection efficiency increases with overvoltage.

Dark count rates

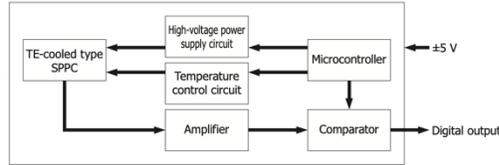


Dark count rate depends on temperature and overvoltage. Typical values at room temperature and recommended overvoltage are $10s - 100s$ c/s , depending on the device design.

After-pulsing



Product example by Hamamatsu (C14463-050GD)

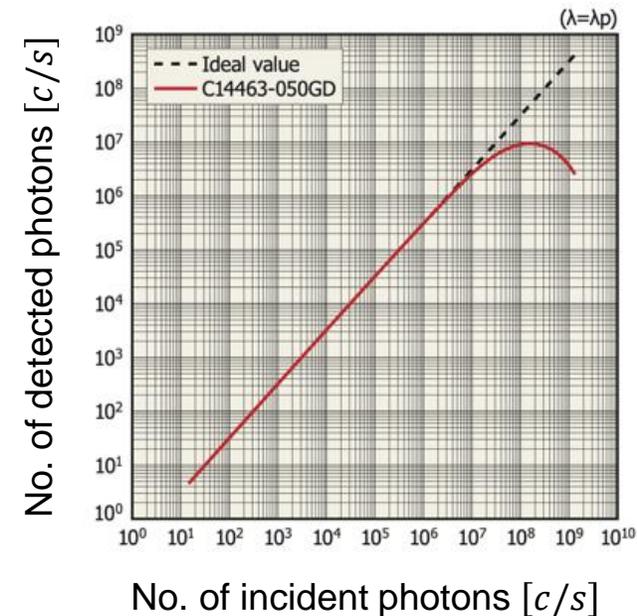
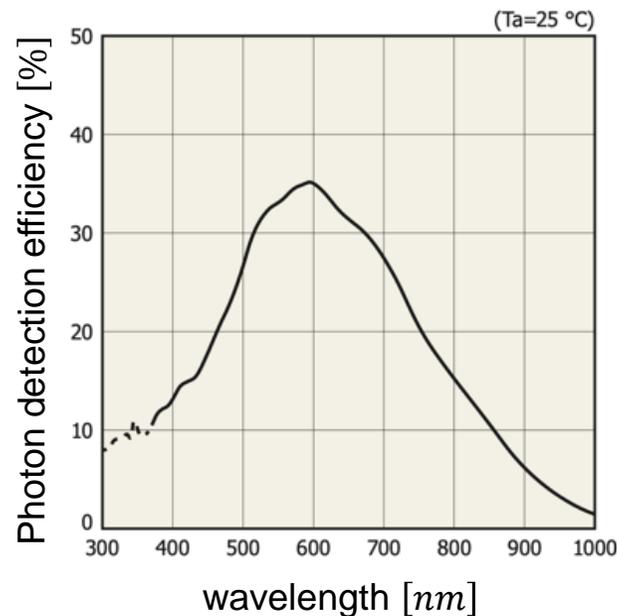


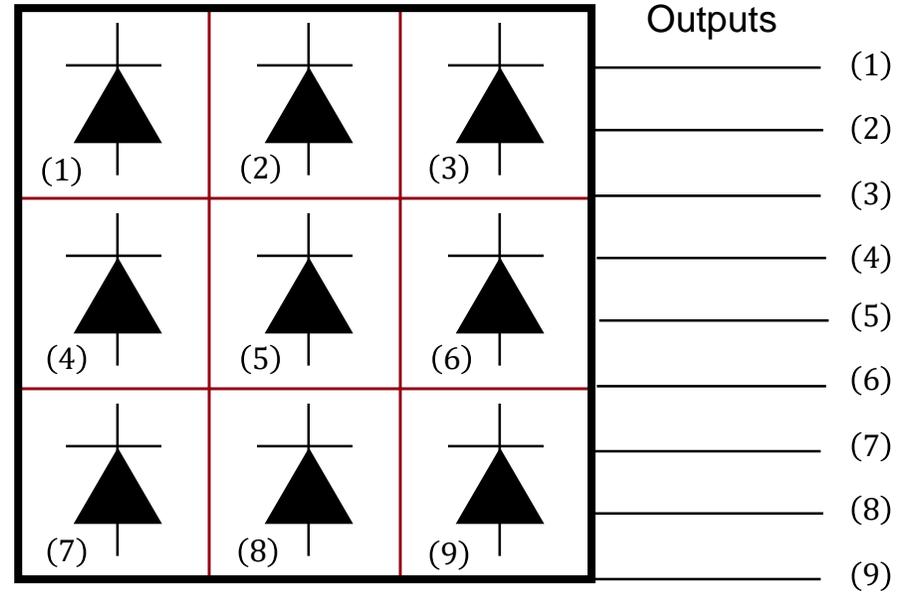
Photon counting module with SPAD (SPPC)

Electrical and optical characteristics (Ta=25 °C, λ=600 nm, Vs=±5 V, unless otherwise noted)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Spectral response range	λ		370 to 1000			nm
Peak sensitivity wavelength	λp		-	600	-	nm
Fiber connector*3	-		FC type			-
Chip temperature (setting temperature)	Tchip		-	-20	-	°C
Photon detection efficiency	PDE		25	35	-	%
Dark count	CD		-	20	60	cps
Afterpulse probability	-	100 ns to 500 ns	-	0.1	-	%
Comparator output	-		TTL compatible			-
Current consumption	Ic	+5 V	-	+200	+1000	mA
		-5 V	-	-20	-40	

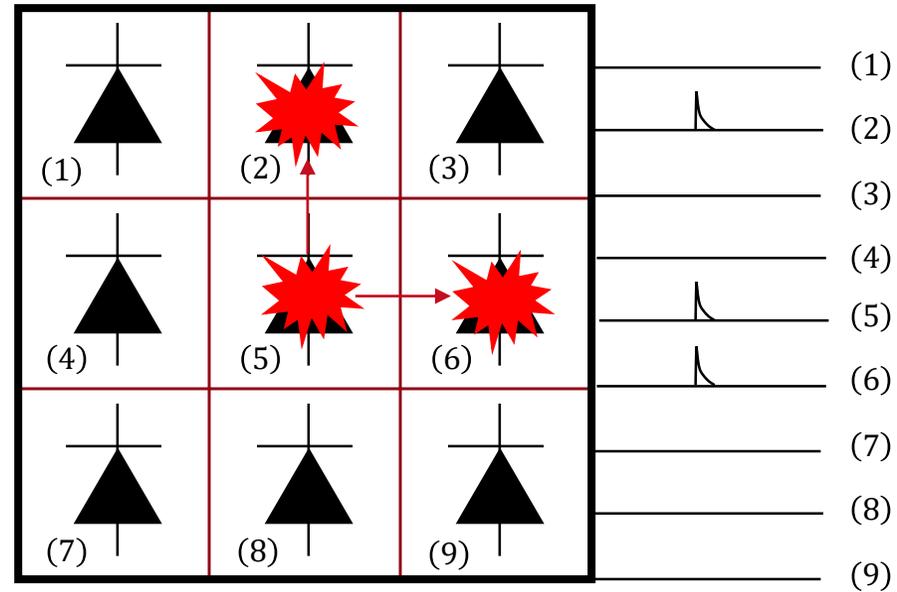
*3: Recommended fiber: GI 50/125 multimode fiber





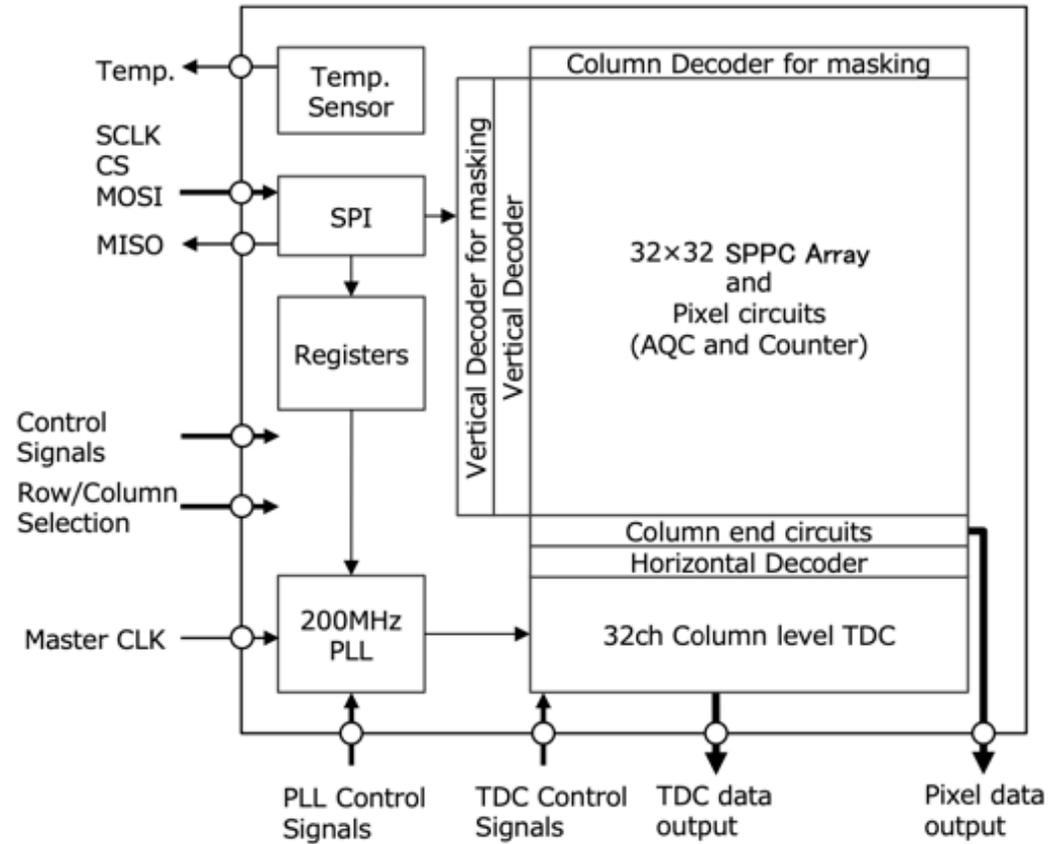
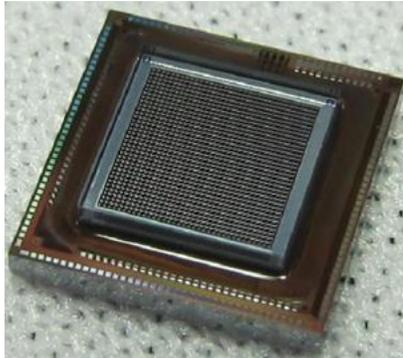
Each element of the array (pixel) has its own quenching circuitry (passive or active).

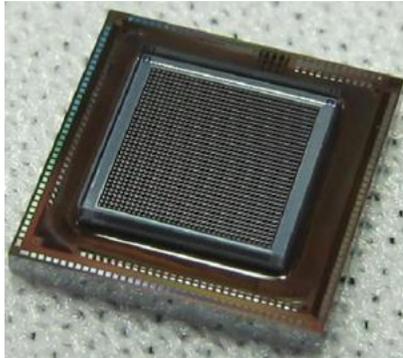
SPAD Array; Crosstalk



Each element of the array (pixel) has its own quenching circuitry (passive or active).

Product example by Hamamatsu (S15008-100NT-01)





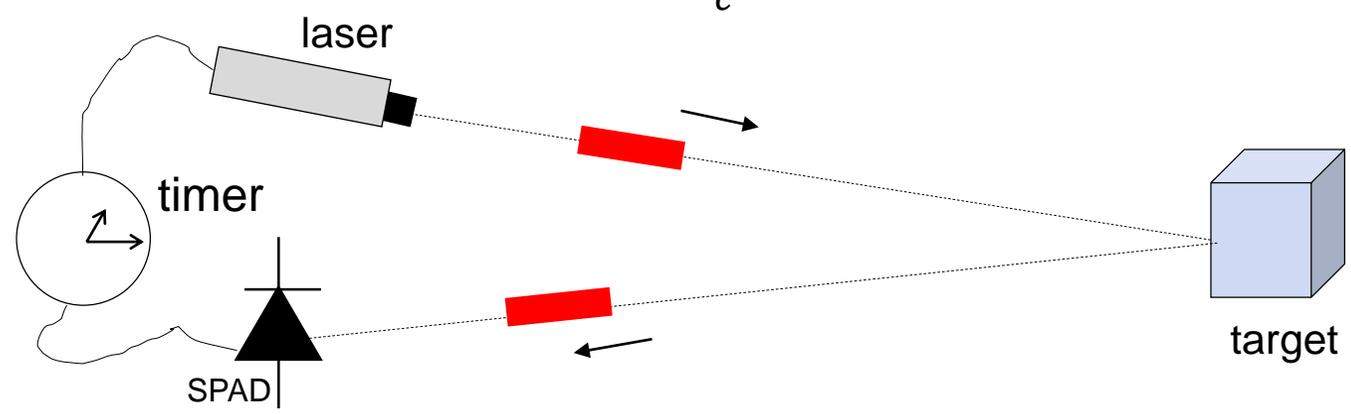
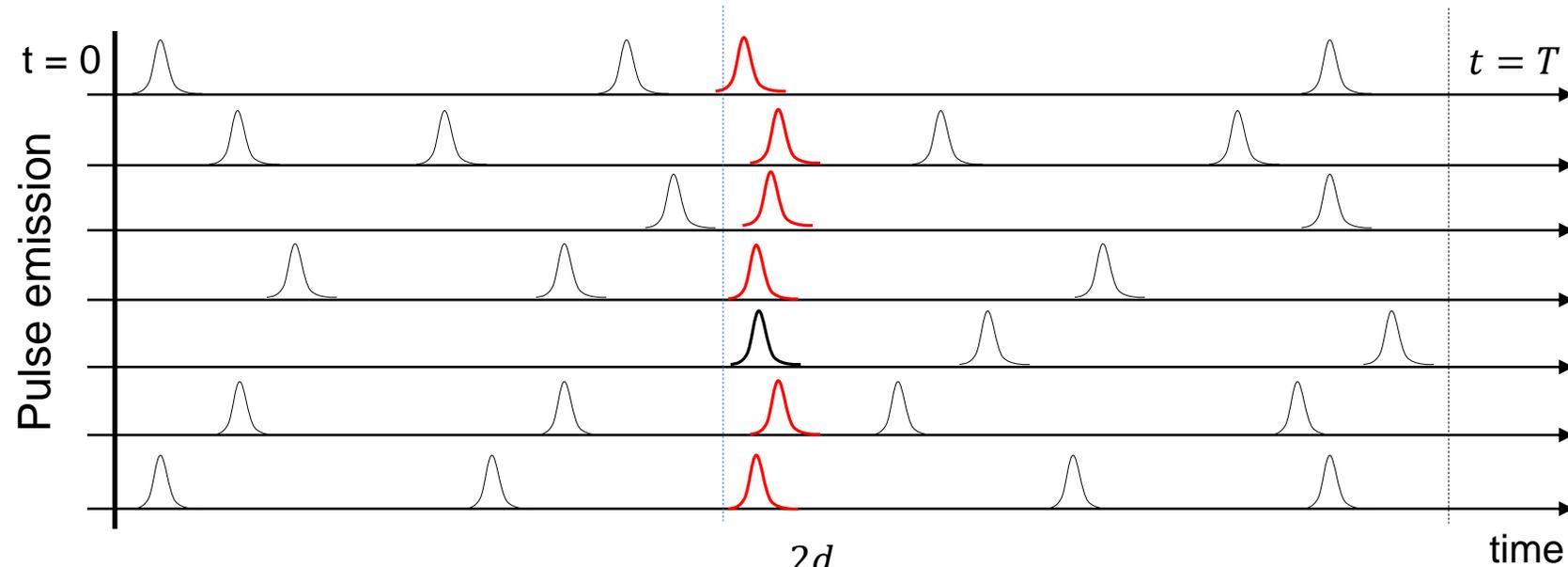
•SPPC Array Specification

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Pixel pitch			-	100	-	μm
Number of pixels			-	32 × 32	-	Ch
Diameter and shapes		Octagonal	-	75 × 75	-	μm
Geometrical fill-factor	FF		-	61	-	%
Peak sensitive wavelength	λ_P		450	500	550	nm
Spectral response region	λ	25°C	380		900	nm
Breakdown voltage	V_{BR}	25°C	50	52	54	V
Temperature coefficient of V_{BR}	ΔT_{VBR}	-20 ~ +30°C		56		mV/°C
Gain	M			1×10^6		-
Photon detection efficiency	PDE	$\lambda = 470$ nm		30		%
		$\lambda = 525$ nm		30		%
		$\lambda = 630$ nm		20		%
Dark count rate	DCR	35°C, $V_e=2.0V$		20k		Hz
Cross talk probability	CT	35°C, $V_e=2.0V$		75		%
Afterpulse probability	AP	50 ns hold-off		3		%

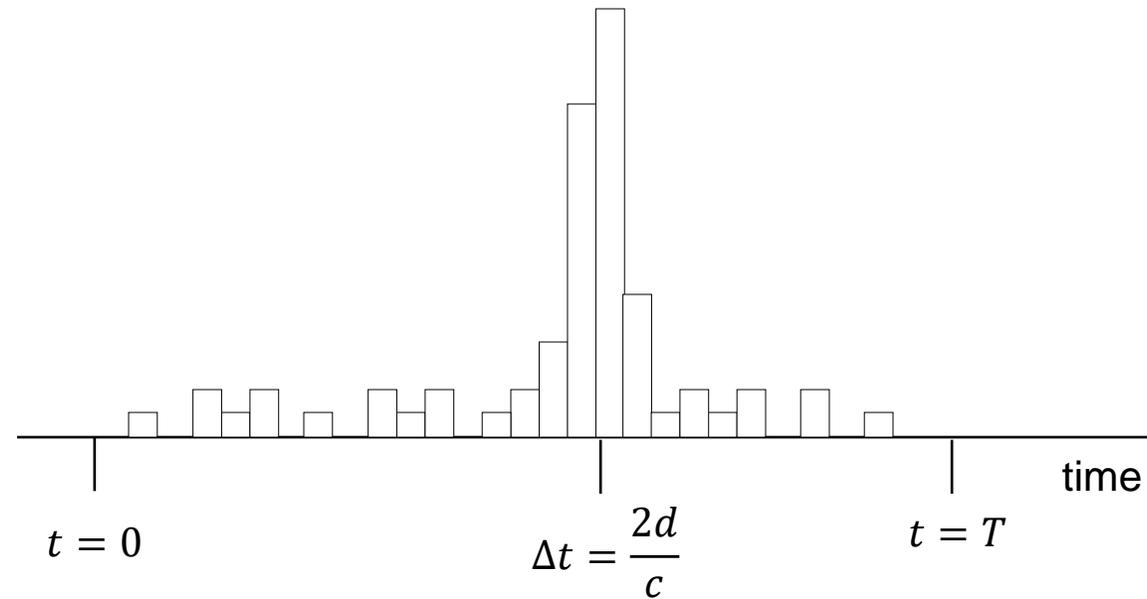
1. The array can be customized to specific user's needs.
2. Hamamatsu is working on improving crosstalk.
3. Hamamatsu is working on higher resolution array (smaller pixels).
4. Hamamatsu is working on IR version of the array.
5. Hamamatsu will work with users on developing customized ASICs
6. Demos are available for evaluation.

Importance of ASIC (example)

Measuring distance with a SPAD



Histogram of trigger times



1. Multiple pulse illumination provides distance information to the target. The information comes from a histogram of trigger times.
2. An ASIC producing such histogram (per pixel) is part of the sensor.

Silicon Photomultiplier (SiPM)

Naming conventions

SiPM – Silicon Photomultiplier

MPPC – Multi-Pixel Photon Counter

} Most-commonly-used names

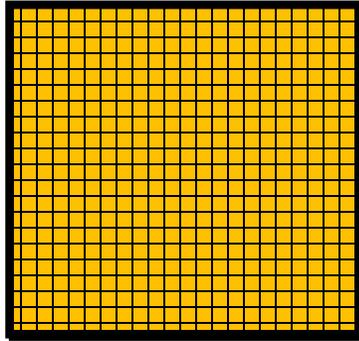
SSPM – Solid-State Photomultiplier

PMAD – Multi-Pixel Avalanche Photodiode

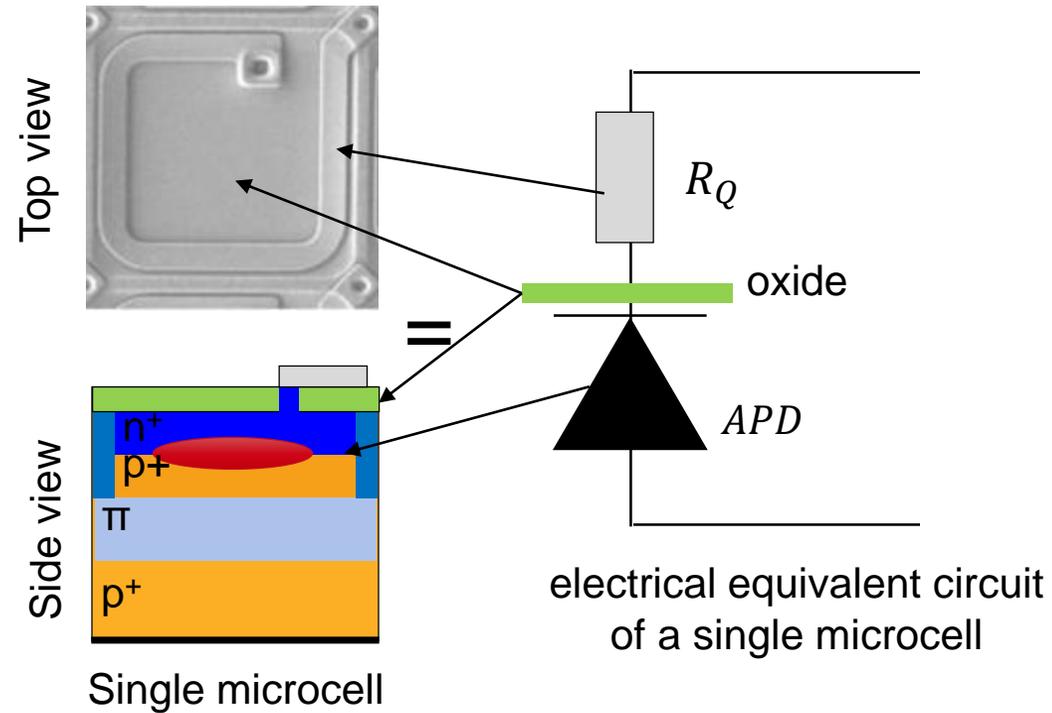
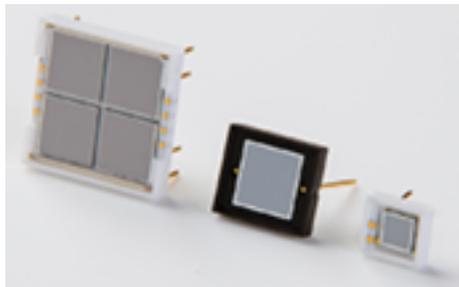
G-APD – Geiger Mode Avalanche Photodiode

MPGM APDs – Multi-Pixel Geiger-Mode Avalanche Photodiodes

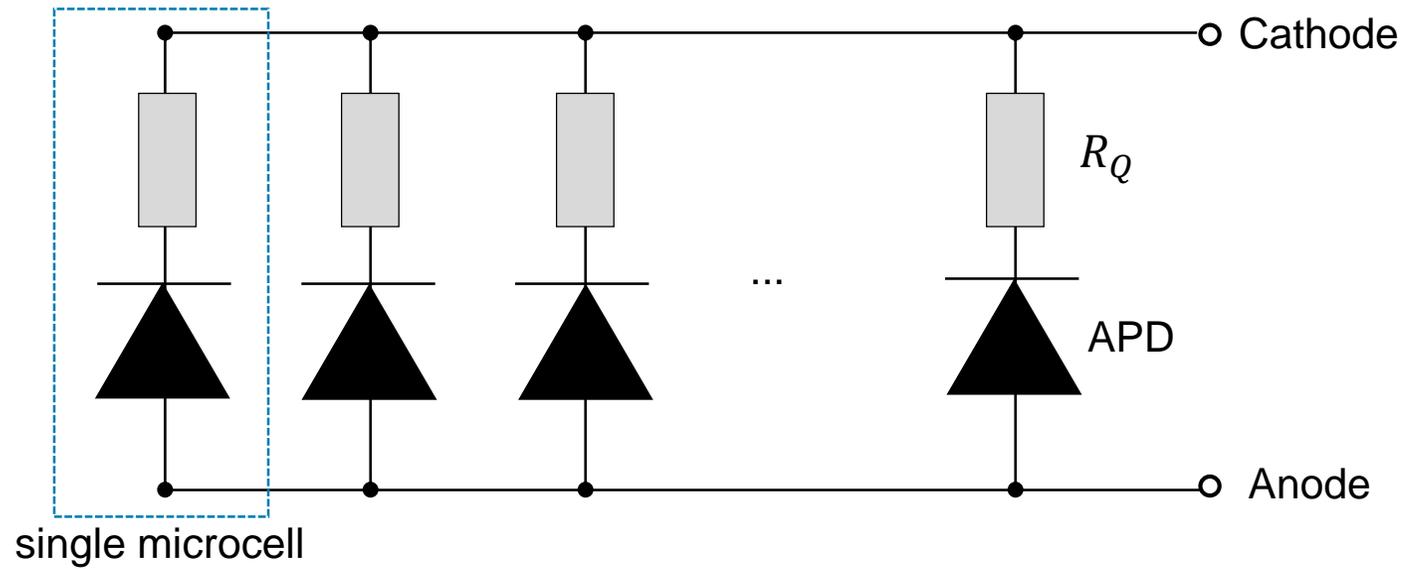
Structure



SiPM is an array of microcells



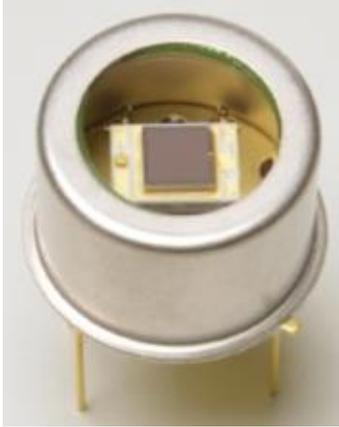
Also known as multi-pixel photon counter (MPPC)



All of the microcells are connected in parallel.

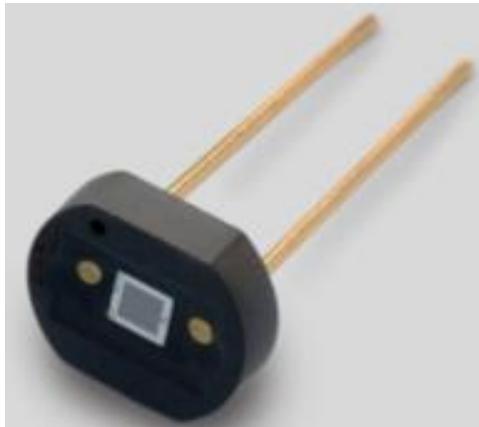
Example of models

S13360-3050DG



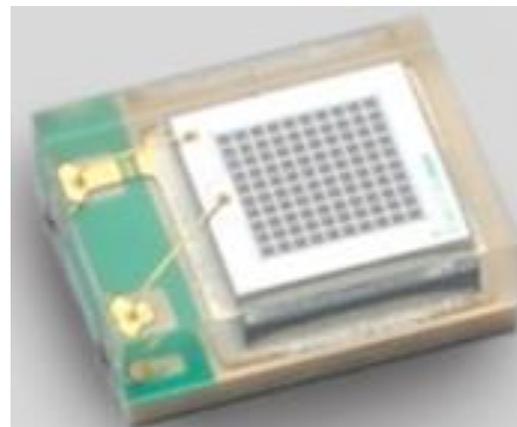
metal can, TE cooled, $3 \times 3 \text{ mm}^2$, 3,600, $50 \times 50 \mu\text{m}^2$

S13360-1325CS



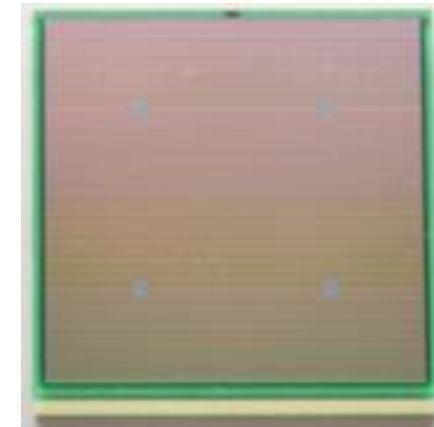
ceramic, $1.3 \times 1.3 \text{ mm}^2$, 2,668, $25 \times 25 \mu\text{m}^2$

S13360-1375PE



surface mount, $1.3 \times 1.3 \text{ mm}^2$, 285, $75 \times 75 \mu\text{m}^2$

S13360-6050VE



surface mount, $6 \times 6 \text{ mm}^2$, 14,555, $50 \times 50 \mu\text{m}^2$

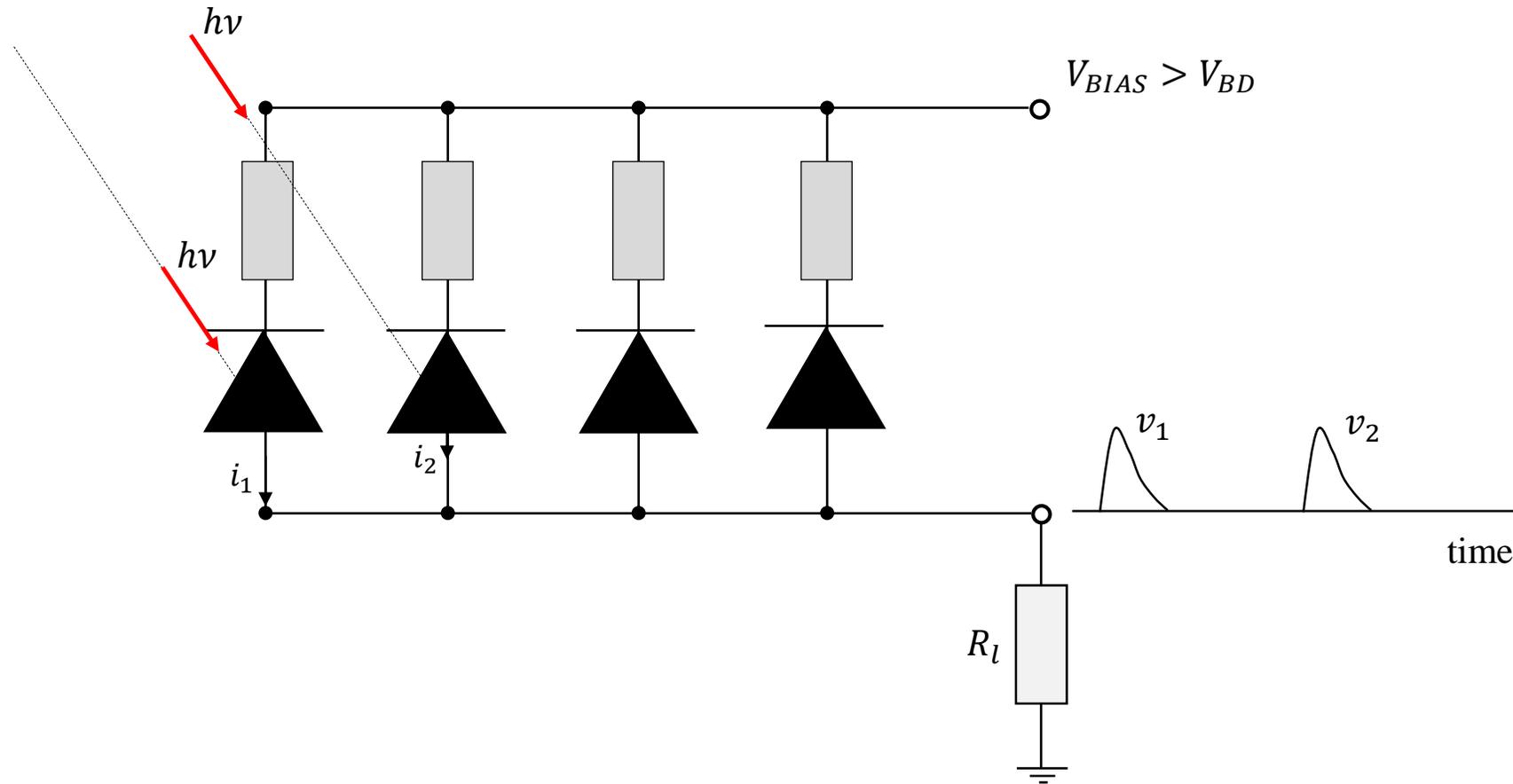
DG – metal can

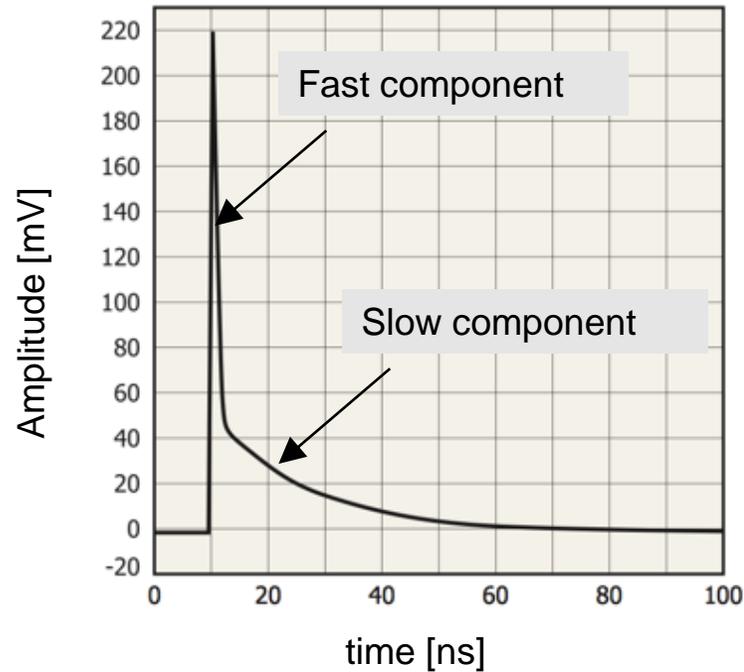
CS – ceramic

PE – surface mount

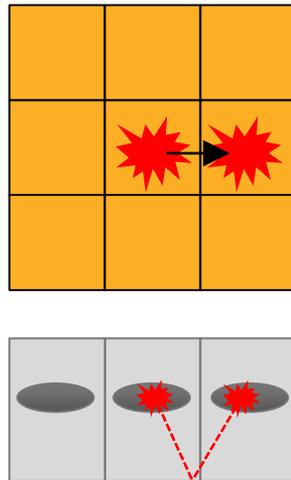
VE – 4-side buttable (best for arrays)

Operation

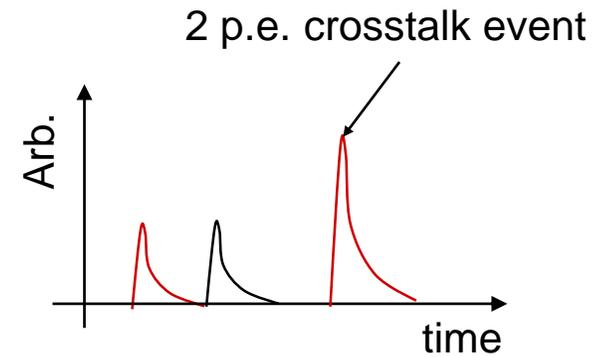




- The RC time constant of the slow component depends on microcell size (all else being equal)
- The recovery time $t_r \approx 5 \times$ the RC time constant
- t_r is on the order of 10s to 100s of ns but in practical situations it is also a function of the detection bandwidth



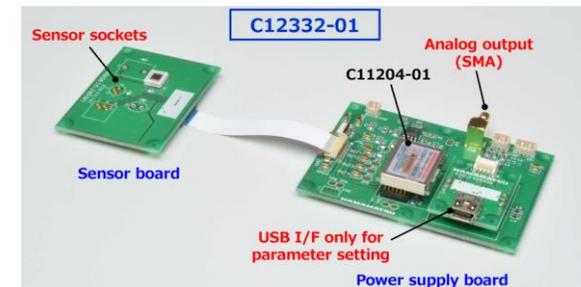
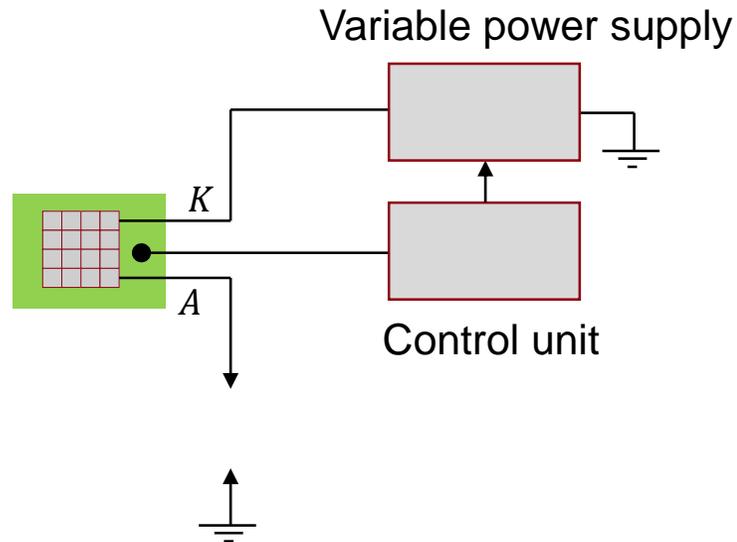
Primary discharge can trigger a secondary discharge in neighboring microcells. This is crosstalk.



Crosstalk probability depends on overvoltage.

Temperature compensation

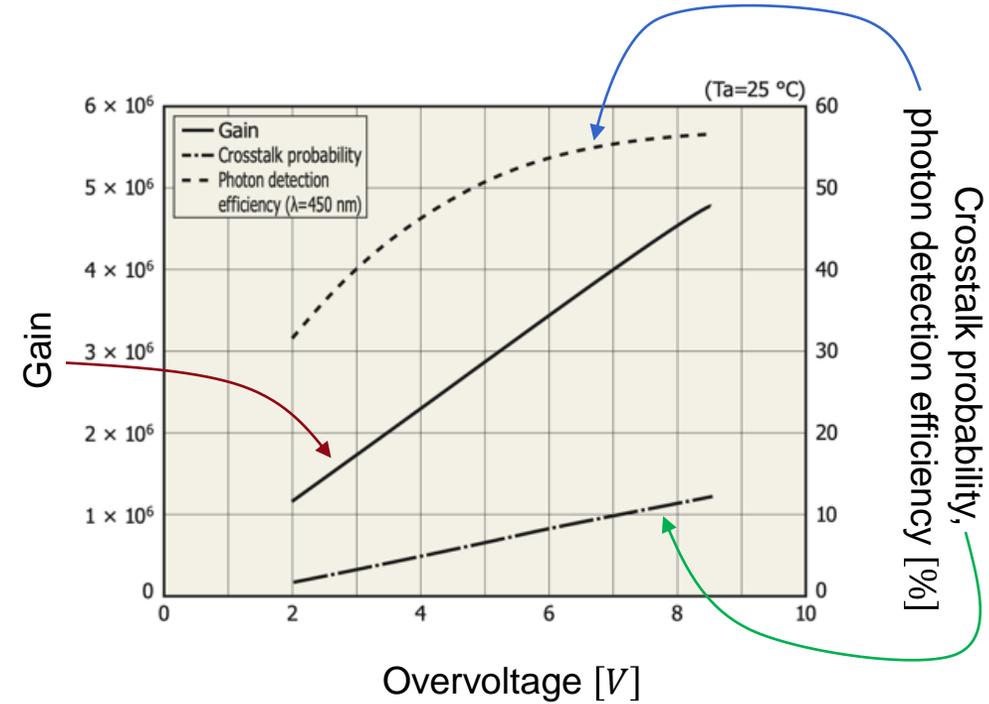
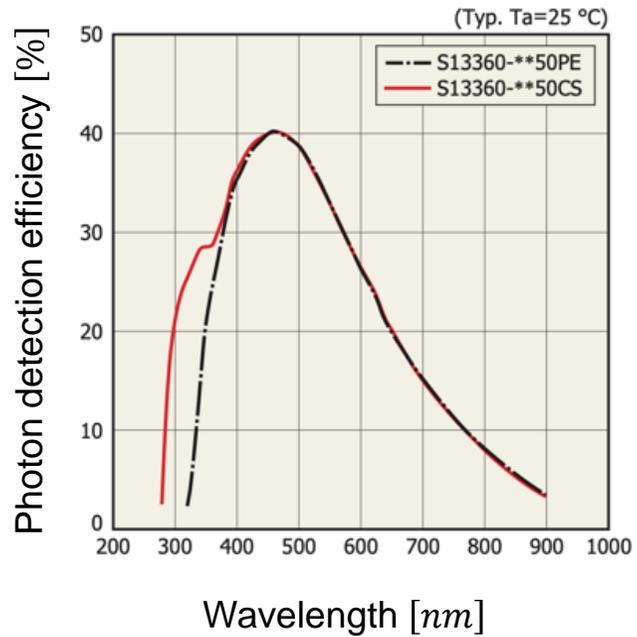
- — Temperature sensor $V_{BD}(T) = V_{BD}(T_0) + \beta(T - T_0)$ (breakdown voltage depends on temperature)



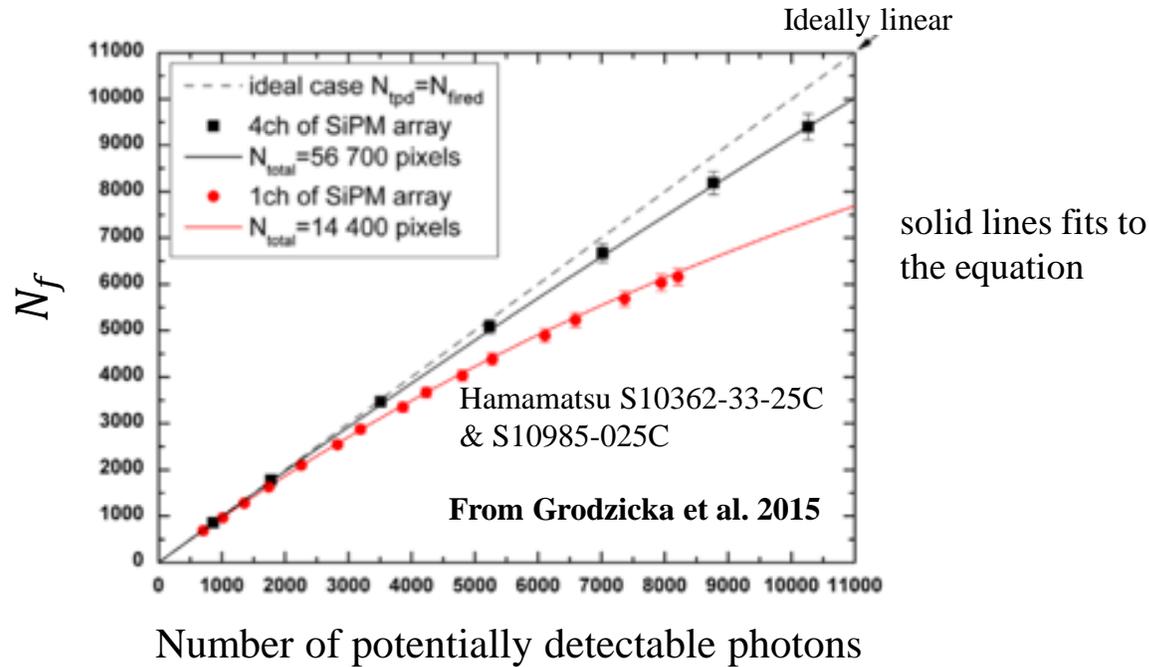
Example of SiPM (MPPC) module with temperature compensation

The role of the control unit is to adjust V_{BIAS} so that the overvoltage ΔV remains constant (and thus gain) as temperature changes.

Product example by Hamamatsu (S13360, 50 μm pitch)



Linearity and dynamic range (δ illumination)



$$N_f = N_t (1 - e^{-N_\gamma \cdot PDE / N_t})$$

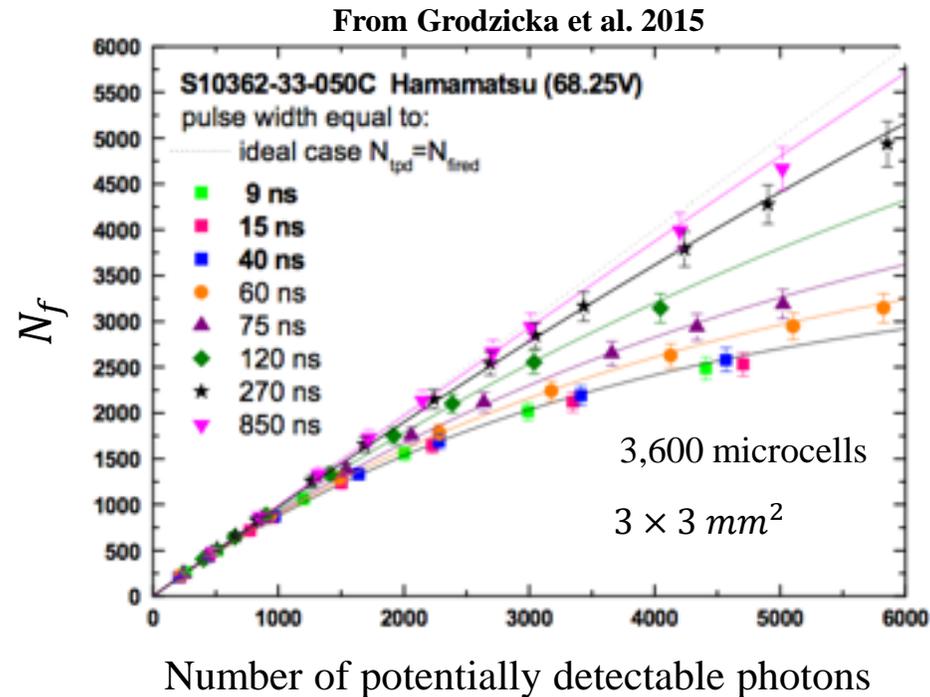
N_t – Number of microcells

N_f – Average number of fired μ -cells

N_γ – Number of photons in a pulse

In the limit of δ –illumination, dynamic range and linearity depend on the number of microcells.

Linearity and dynamic range (finite-pulse illumination)



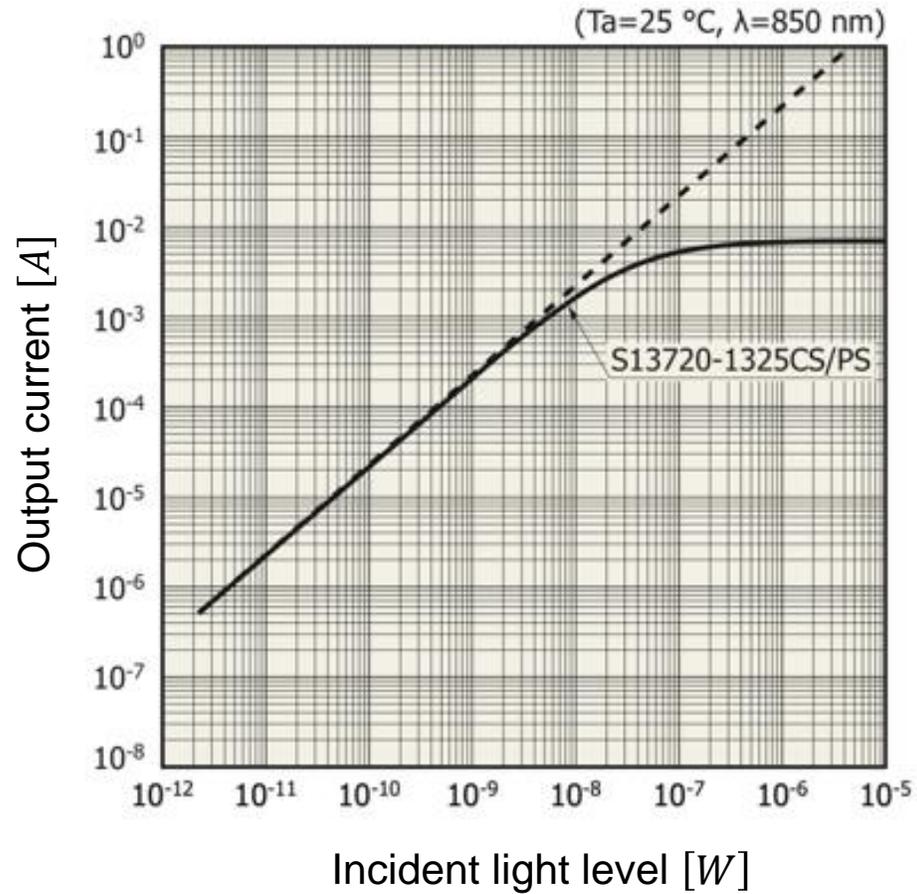
$$N_f = N_t \left(\frac{T_P}{t_r} \right) \left(1 - \exp \frac{-N_\gamma \cdot PDE}{\left(\frac{T_P}{t_r} \right) N_t} \right)$$

T_P – Pulse duration

t_r – Recovery time

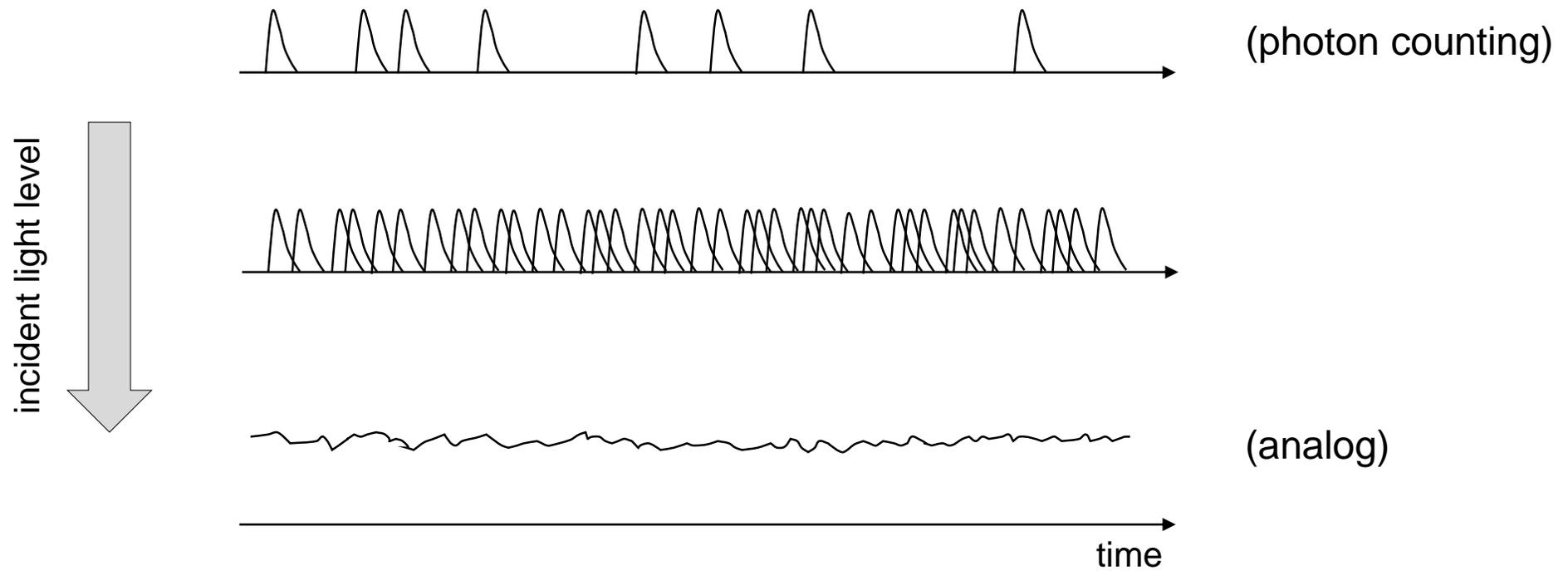
For a given number of photons in a pulse, the number of effective fired microcells increases with the pulse duration.

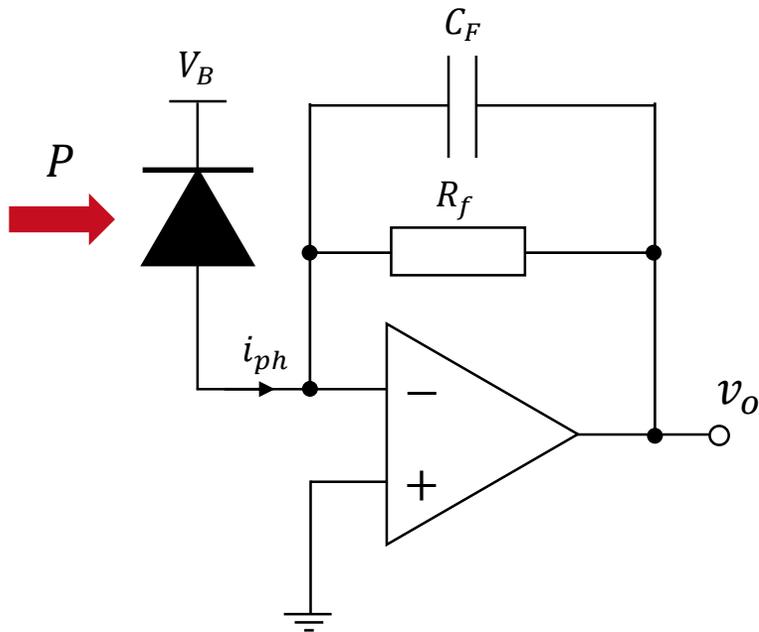
Linearity and dynamic range (DC)



For some SiPMs Hamamatsu provides a linearity plot for DC illumination. This plot can be transcribed from $\lambda = 850\text{ nm}$ to any other wavelength.

Modes of operation





$$i_{ph} = e\mu(1 + P_{ct}) \frac{PDE \cdot P \cdot \lambda}{hc}$$

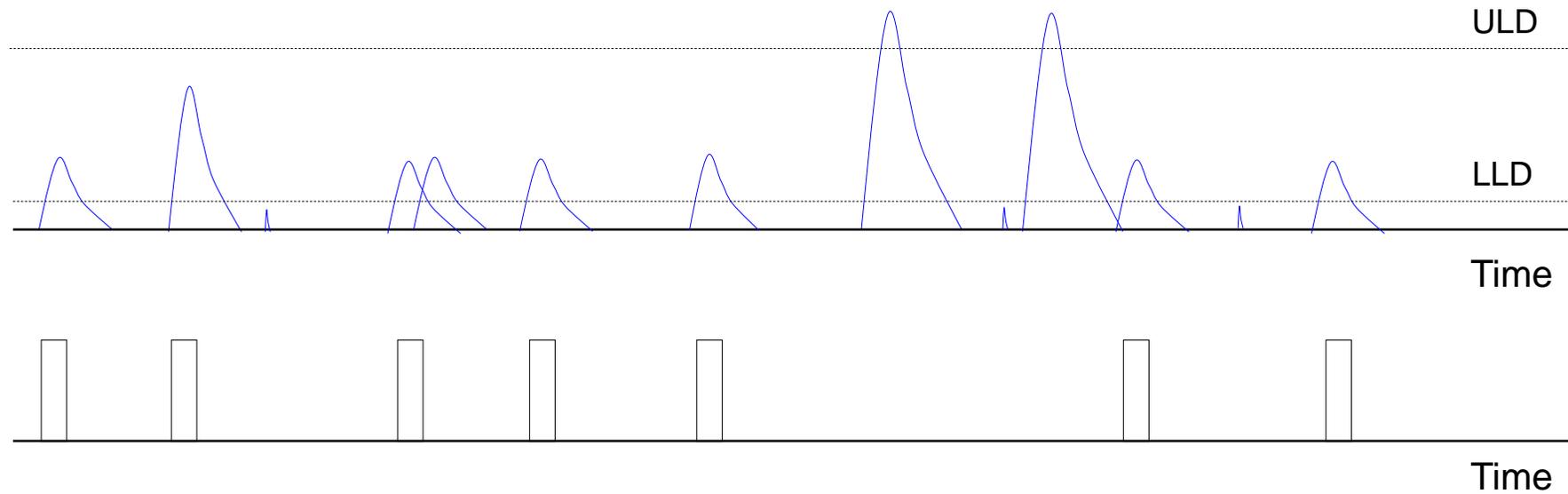
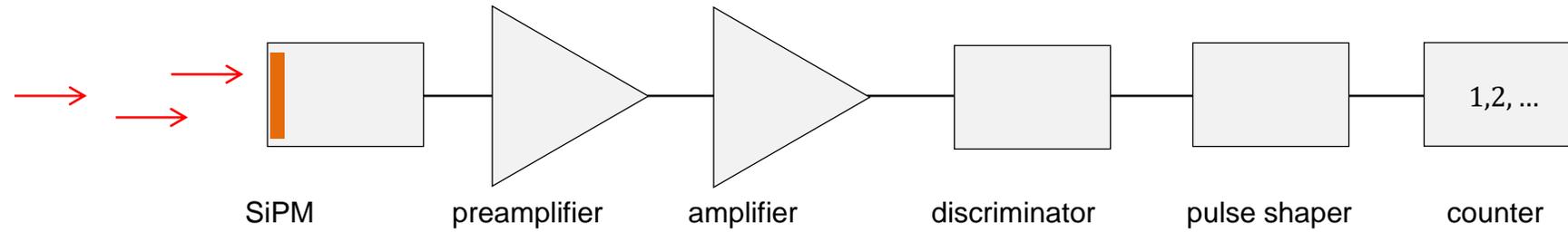
$$\frac{S}{N} = \frac{i_{ph} R_f}{\sqrt{i_{SS}^2 R_f^2 + i_{DS}^2 R_f^2 + \frac{4kT\Delta f}{R_f} R_f^2}}$$

$$i_{SS}^2 = 2ei_{ph}\mu F\Delta f \quad (\text{signal photon shot noise})$$

$$i_{DS}^2 = 2ei_D\mu F\Delta f \quad (\text{dark current shot noise})$$

$$i_J^2 = \frac{4kT\Delta f}{R_f} \quad (\text{Johnson noise of the feedback resistor})$$

Photon counting



$$\frac{S}{N} = \frac{n_S \sqrt{T_{exp}}}{\sqrt{n_S + 2(n_B + n_D)}}$$

T_{exp} – measurement time

$$n_S = n_{tot} - (n_B + n_D)$$

n_{tot} – number of counts per unit time due to “science” light, background light, and dark counts

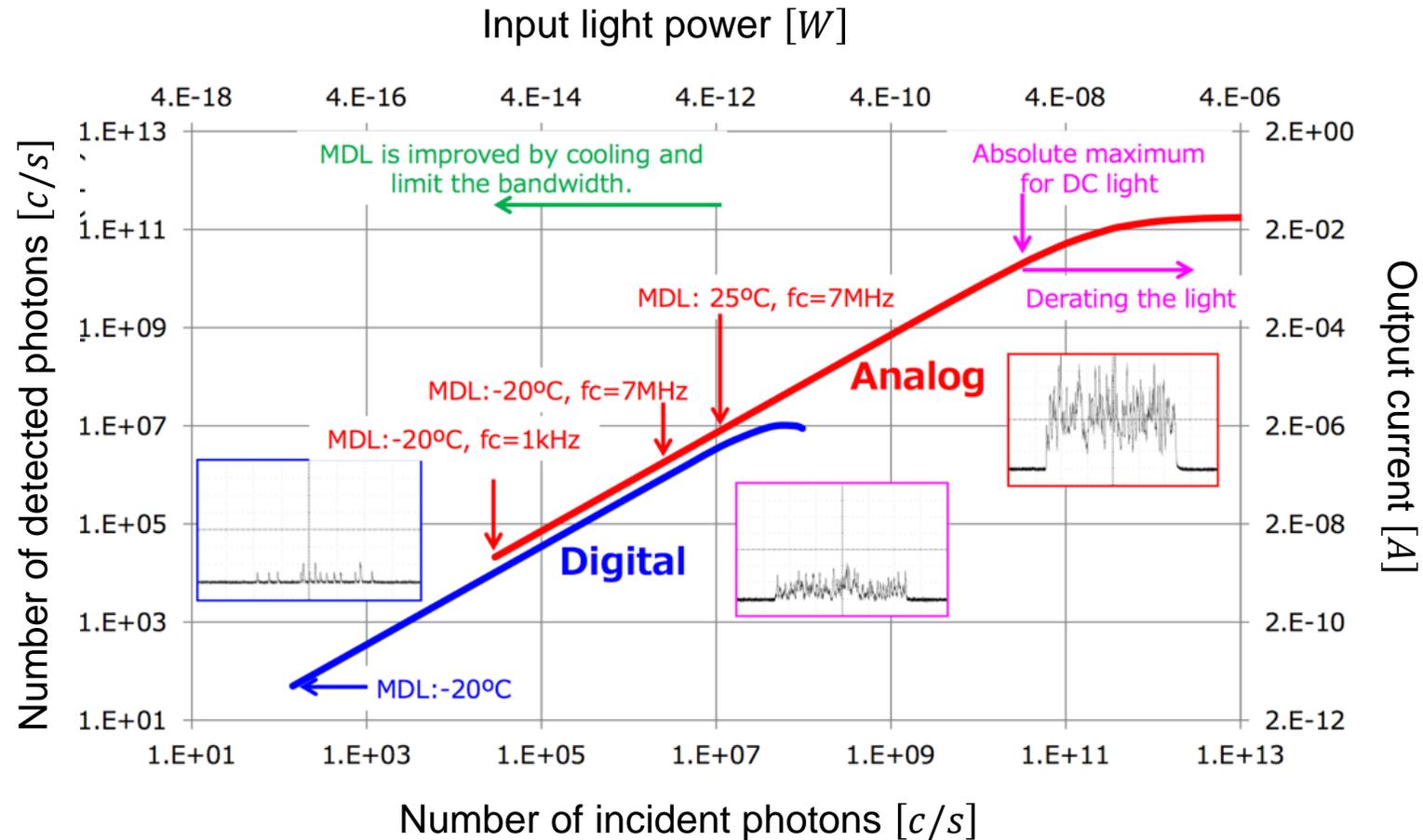
n_B – number of counts per unit time due to background light

n_D – number of counts per unit time due to dark current

All rates are measured with the same exposure time T_{exp}

Modes of operation

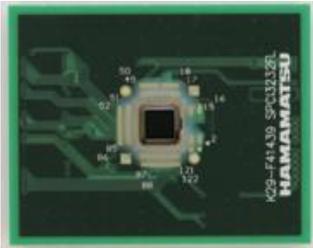
3 × 3 mm², 50 μm



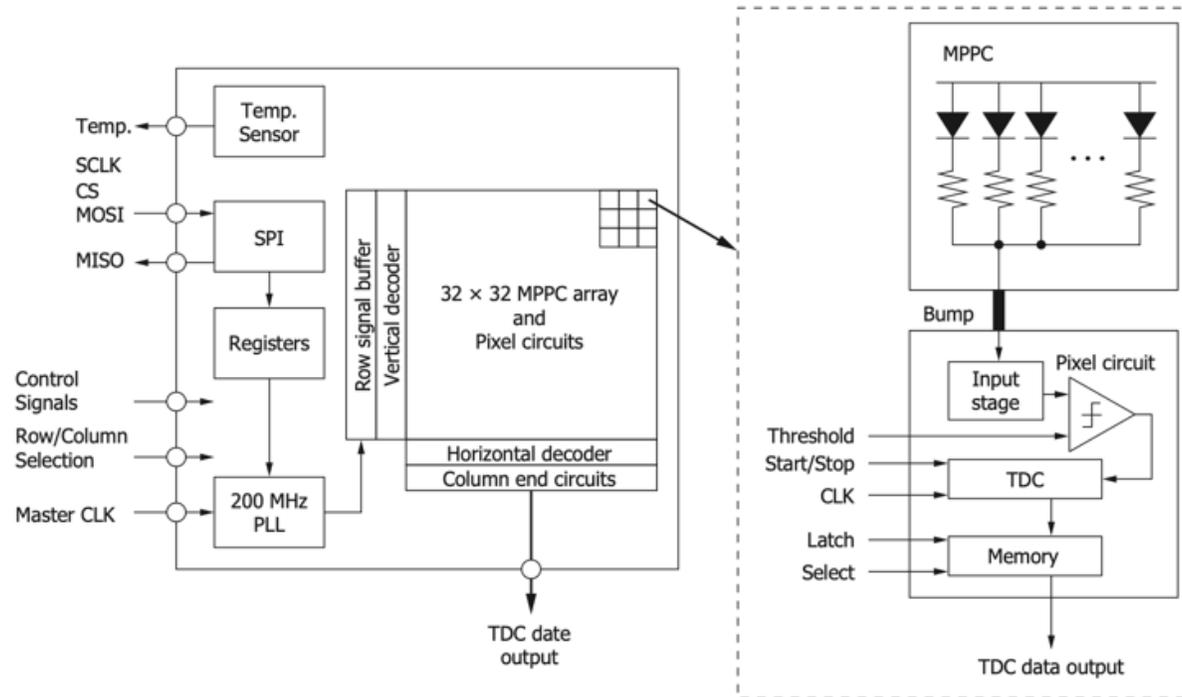
Minimum detection limit (MDL) can be lowered by cooling and limiting the detection bandwidth.

SiPM imaging array, product example by Hamamatsu

S15013-0125NP-01



2D MPPC photon counting image sensor



This array can be used for imaging and for ToF distance measurement (e.g., in flash LiDAR).

SiPM imaging array, product example by Hamamatsu

Structure

Parameter	Symbol	Value	Unit
MPPC type	-	Equivalent to S14420 series	-
Number of channels	-	32 × 32	ch
Effective photosensitive area / channel	-	100 × 100	μm
Pixel pitch	-	25	μm
Number of pixels / channel	-	12	-
Fill factor	-	36.4	%
Package type	-	Connector	-
Window	-	Borosilicate glass	-
Reflective index of window materials	-	1.51	-

Electrical and optical characteristics (Ta=25 °C)

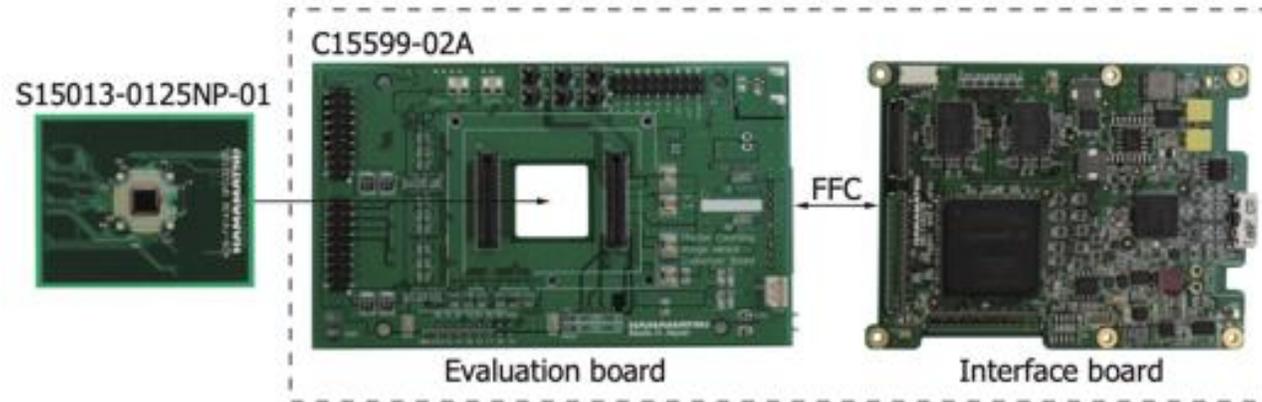
Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Spectral response range	λ		550 to 1050			nm
Peak sensitivity wavelength	λp		-	840	-	nm
Photon detection efficiency*2	PDE	λ=910 nm	-	6	-	%
Dark count*3		Vop	-	2	-	kcps
Breakdown voltage	VBR		-47.5	-42.5	-37.5	V
Recommended operating voltage	Vop		-	VBR - 5	-	V
Gain	M	Vop	-	1.0 × 10 ⁶	-	-
Temperature coefficient of VOP	ΔTVOP		-	47	-	mV/°C
Frame rate			-	10	-	kfps
PLL frequency	FPLL		180	200	220	MHz
TDC full-scale range		FPLL=200 MHz	-	-	10.24	μs
TDC resolution		FPLL=200 MHz	-	312.5	-	ps
TDC jitter		FWHM, FPLL=200 MHz	-	135	-	ps

*2: Photon detection efficiency does not include crosstalk or afterpulses.

*3: Threshold=0.5 p.e.

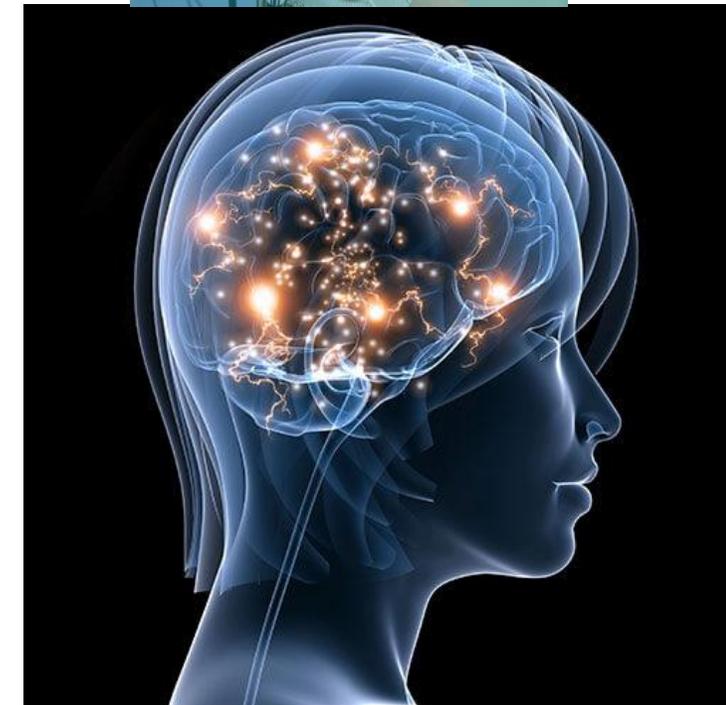
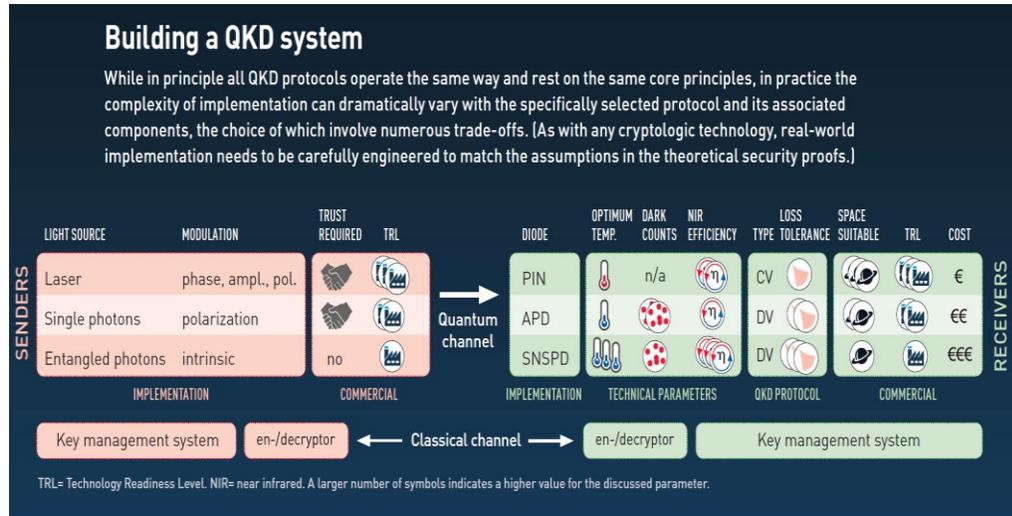
Note: The above characteristics were measured the operating voltage that yields the listed gain in this catalog. (See the data attached to each product.)

SiPM imaging array, product example by Hamamatsu



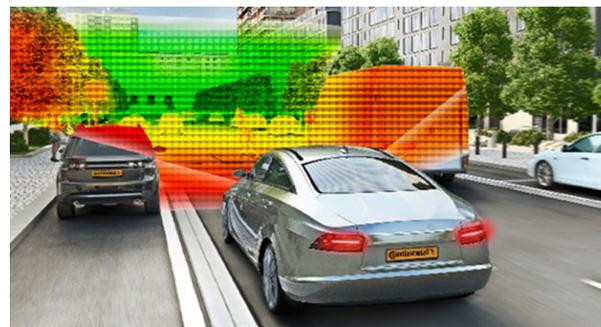
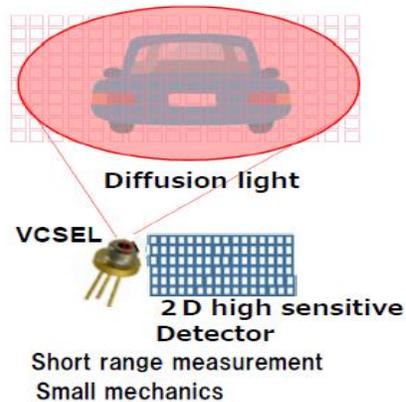
Demo units, together with evaluation and interface boards, are available to potential users.

Future Applications for SPAD Arrays



Brain Activity Monitoring

Quantum Technology – Quantum Key Distribution



Solid State Flash LiDAR

1. Photon counting can be a preferred detection technique when the incident light level is low.
2. SPAD and SiPM are well-suited for photon counting.
3. SPAD and SiPM image sensors are being developed.
4. Research and development continues to extend the detection into the IR regime.
5. Integration of ASICs with the SPAD or SiPM imagers is the most cost-effective approach.
Hamamatsu provides support and will work with individual customers to provide solutions.

Join Us for 10 Weeks of FREE Photonics Webinars (17 Topics)

Week #	Weekly Topics	# of Talks	Talk #1 Date	Talk #2 Date
1	Introduction to Photodetectors	2	26-May-20	28-May-20
2	Emerging Applications - LiDAR & Flow Cytometry	2	2-Jun-20	4-Jun-20
3	Understanding Spectrometer	2	9-Jun-20	11-Jun-20
1 Week Break				
4	Specialty Products – Introduction to Light Sources & X-Ray	2	23-Jun-20	25-Jun-20
5	Introduction to Image Sensors	2	30-Jun-20	02-Jul-20
1 Week Break				
6	Specialty Products – Laser Driven Light Sources	2	14-Jul-20	16-Jul-20
7	Image Sensor Circuits and Scientific Camera	2	21-Jul-20	23-Jul-20
8	Mid-Infrared (MIR) Technologies & Applications	2	28-Jul-20	30-Jul-20
1 Week Break				
9	Photon Counting Detectors – SiPM and SPAD	1	11-Aug-20	
10	Using SNR Simulation to Select a Photodetector	1	18-Aug-20	

To register for other webinars or hear previous webinar recordings, please visit link below:

<https://www.hamamatsu.com/us/en/news/event/2020/20200526220000.html>

Thank you

Thank you for listening.

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